

Development of New Photodetectors

Bob Wagner, Argonne National Laboratory
Fermilab Workshop on Detector R&D
Friday 08 October 2010

The Charge

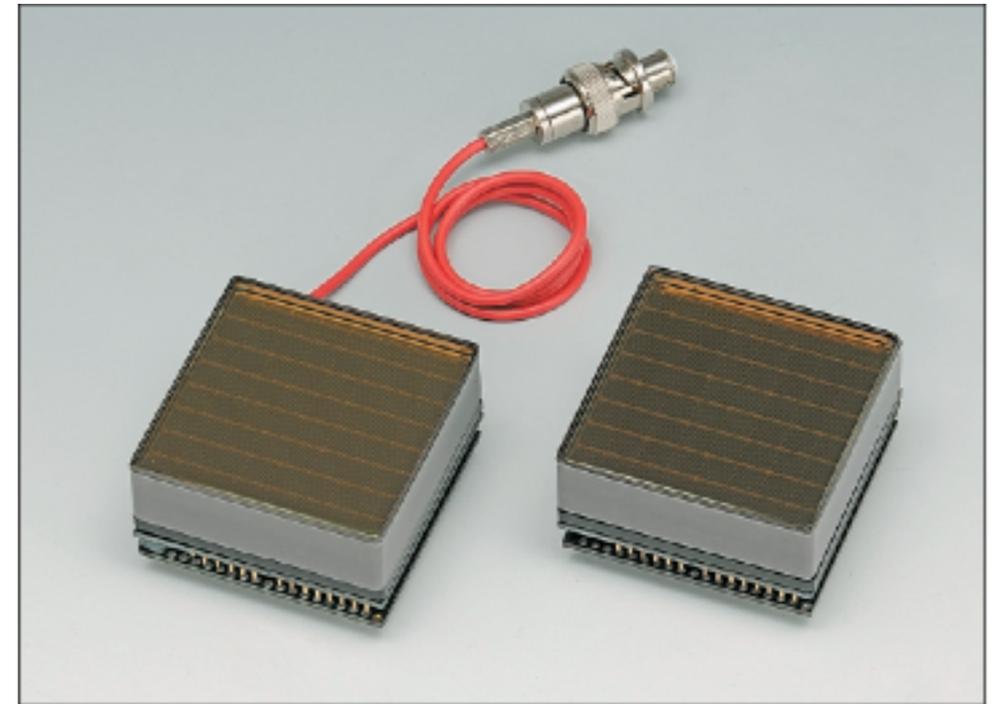
- ▶ State of Relevant Detectors Now -- Appropriate for Upgrades
 - Conventional PMTs
 - Hybrid Photodetectors
 - Geiger Mode Avalanche Photodetectors/Silicon Photomultipliers (J. Va'vra talk)
 - Microchannel Plate Photodetectors
- ▶ What Drives Upgrades (Improved Photodetectors)?
 - Lower Cost per Channel
 - Higher Photon Detection Efficiency
 - Improved Timing Precision
 - Finer Energy Resolution
 - Spatial Resolution
 - High Data Rate
- ▶ “Pie-in-the-Sky” Technology for Addressing New Physics
- ▶ “Cut-and-Dried” Technology
- ▶ Timescales
- ▶ Focus Now, Near Future, Far Future



Conventional Photomultiplier Tubes

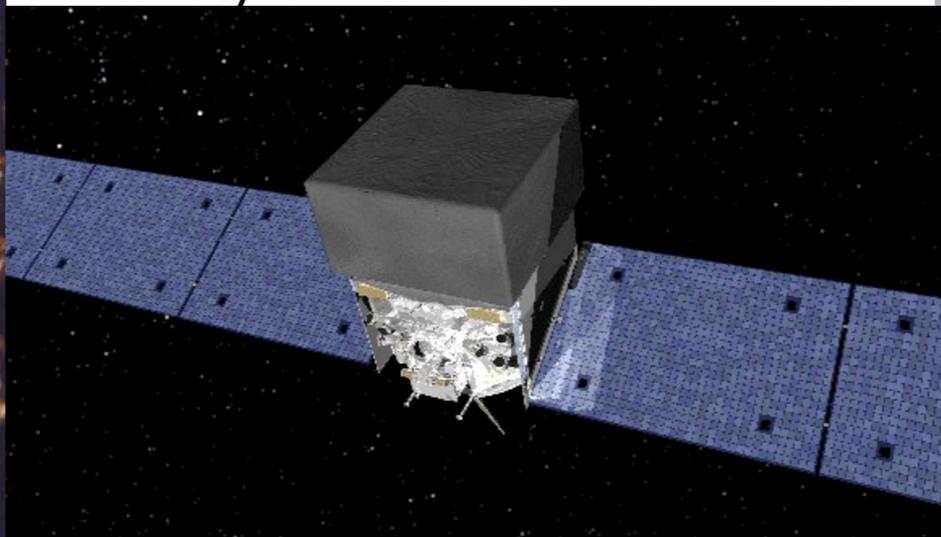
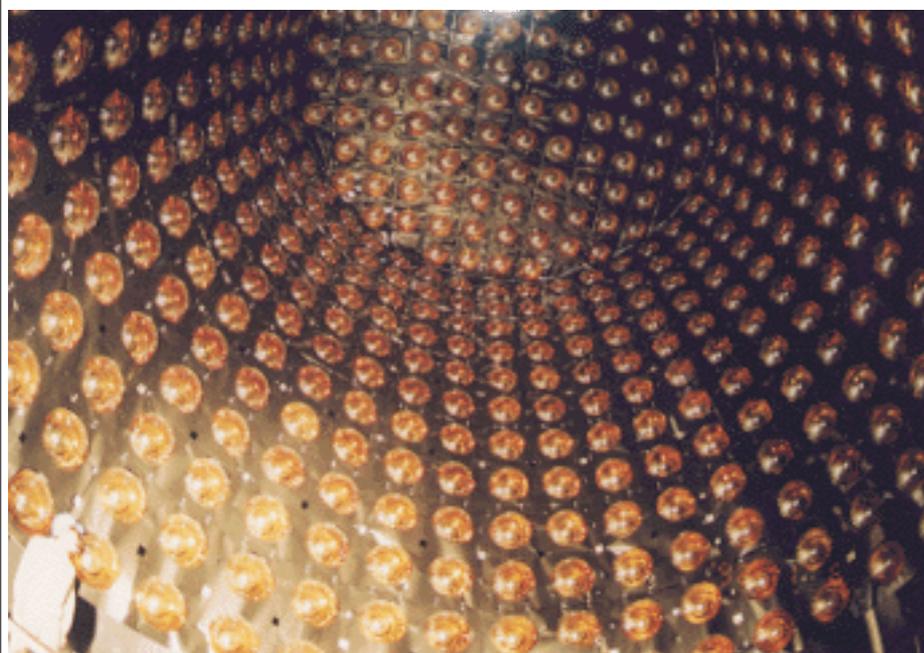


- ▶ “Cut-and-Dried” Technology
 - has been in use for decades
 - robust, generally low noise
 - simple biasing
- ▶ Low Profile Multi-anode PMTs readily available
 - lower cost readout per channel – fiber
 - good spatial resolution for imaging



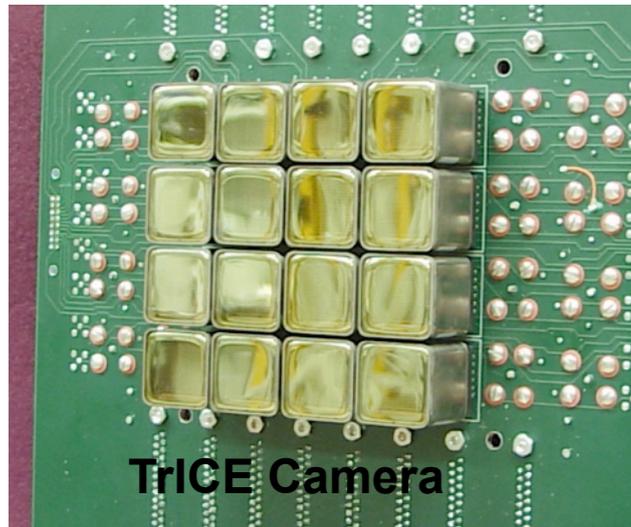
Left: H8500C (HV cable input type), Right: H8500D (HV pin input type)

Photomultipliers operate in a variety of harsh environments

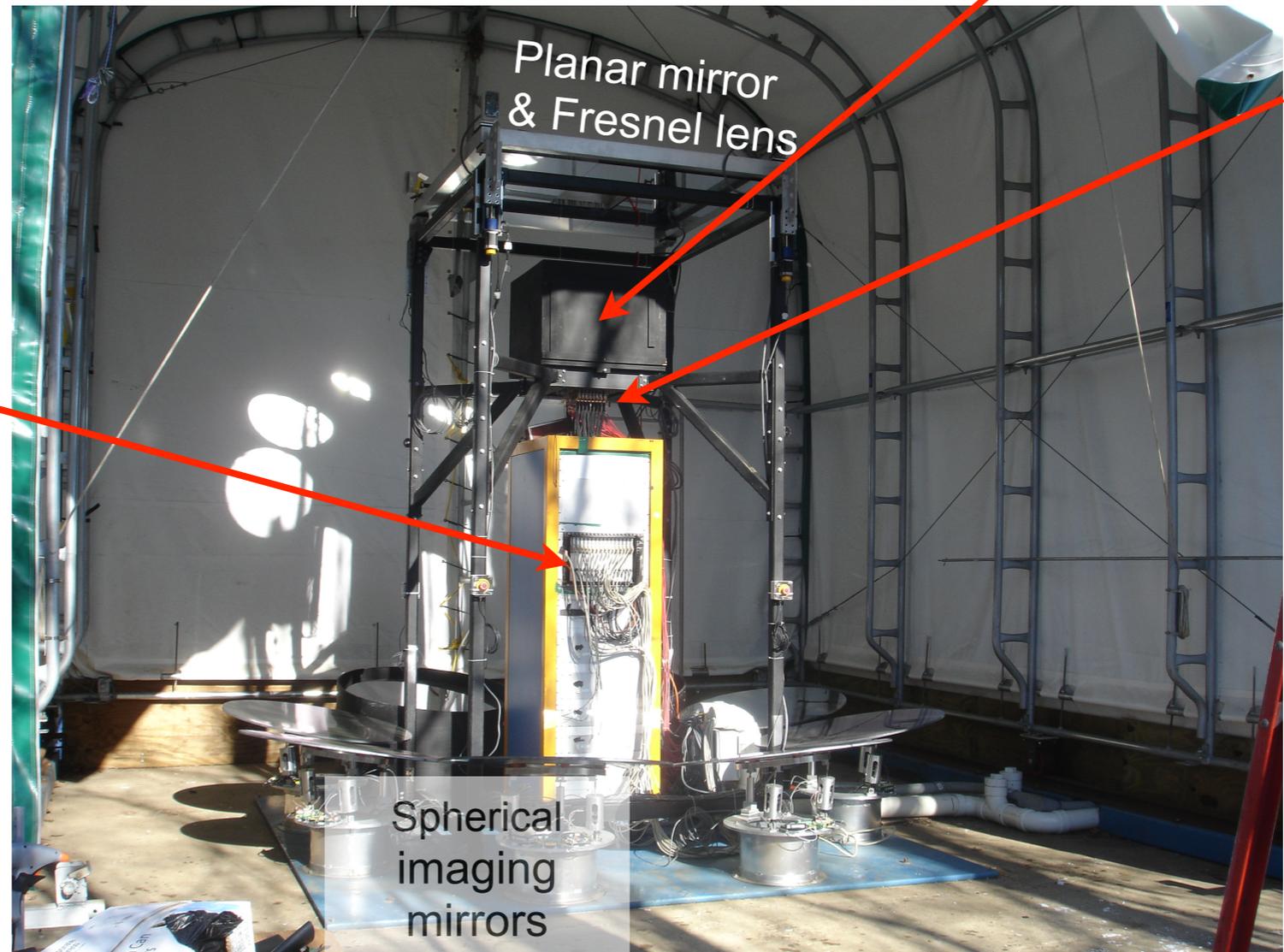
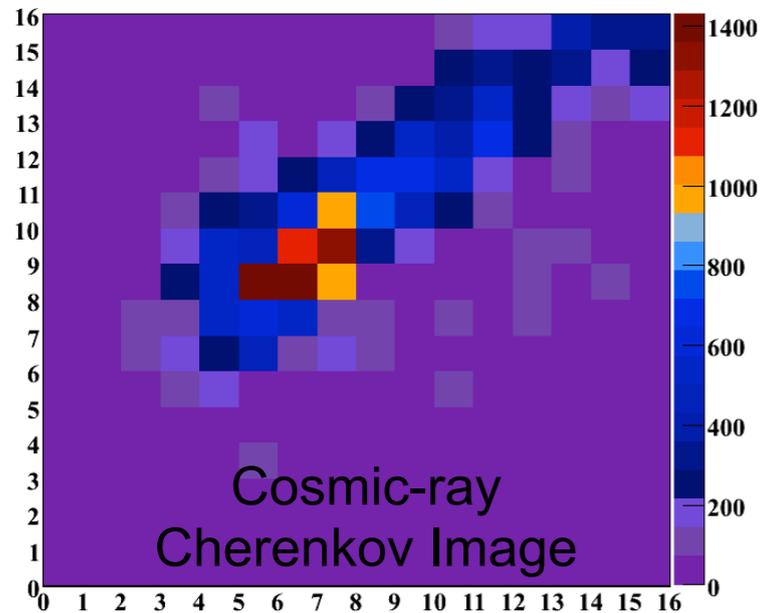


Imaging with Multi-Anode Phototubes

R8900 16 pixel (6×6mm²) MAPMTs

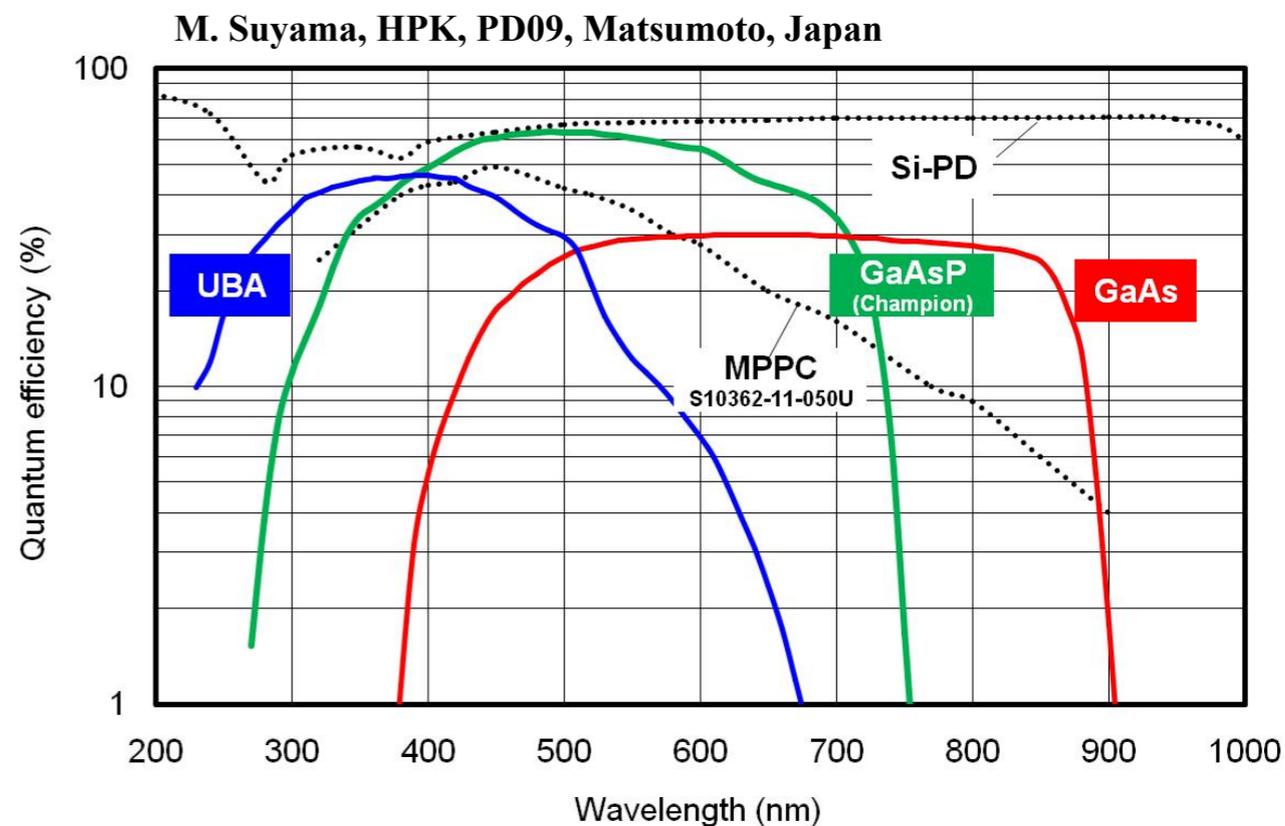
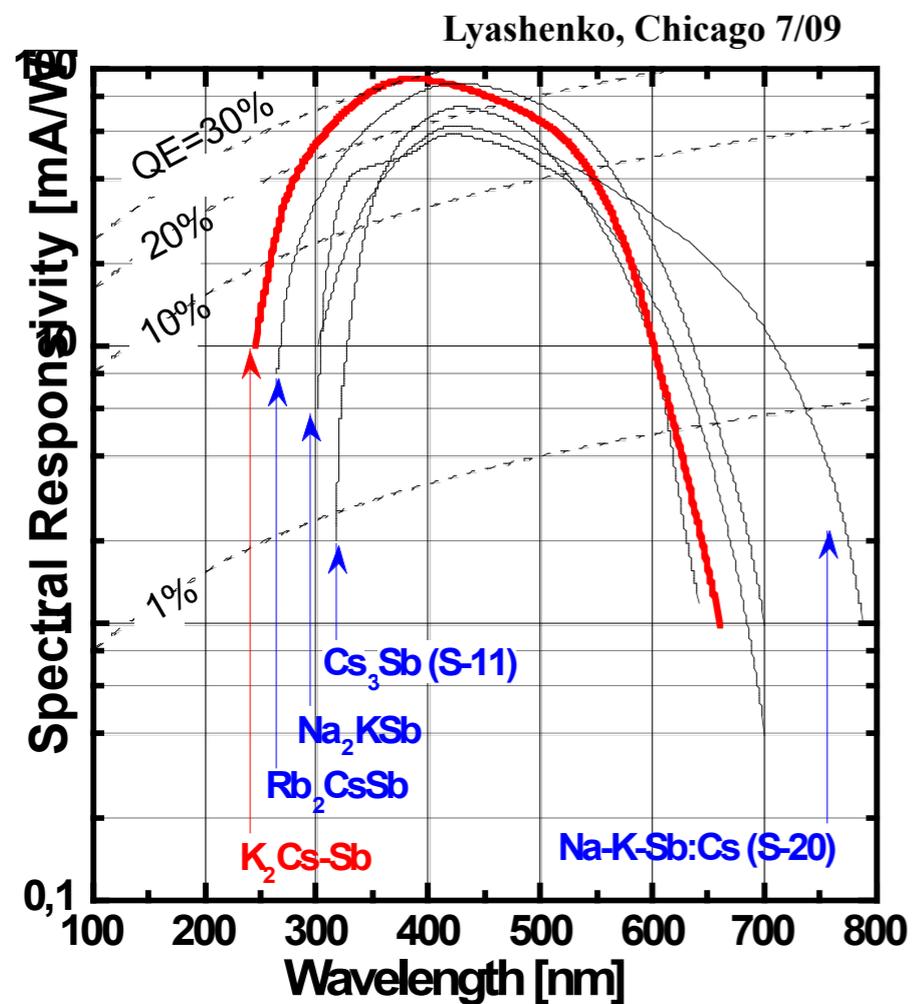


Digitization electronics



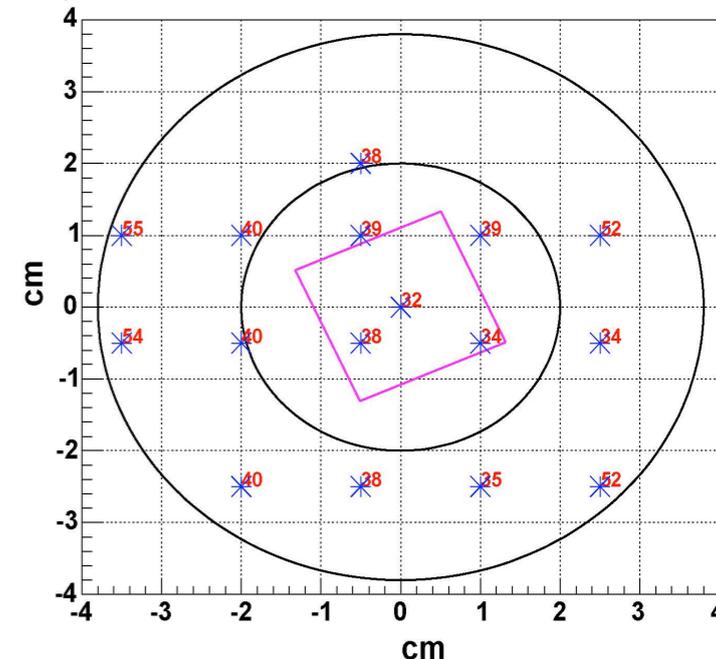
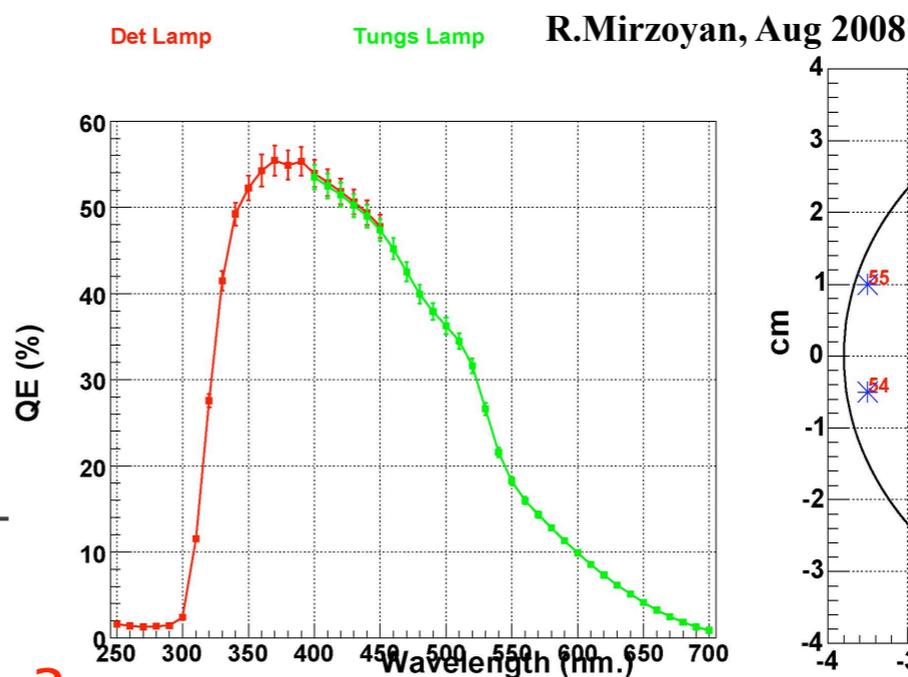
TrICE Telescope -- located at Argonne Natl. Lab.

Improving Conventional Photomultipliers -- QE



- ▶ Typical multi-alkali QE ~ 15–30%
- ▶ In past few years, Hamamatsu marketing super- & ultra-bialkali with QE 35–45%
- ▶ One of kind higher QE (~50%) PMT has been produced
 - Restricted to specific locations on PMT

How to achieve high QE reproducibly?



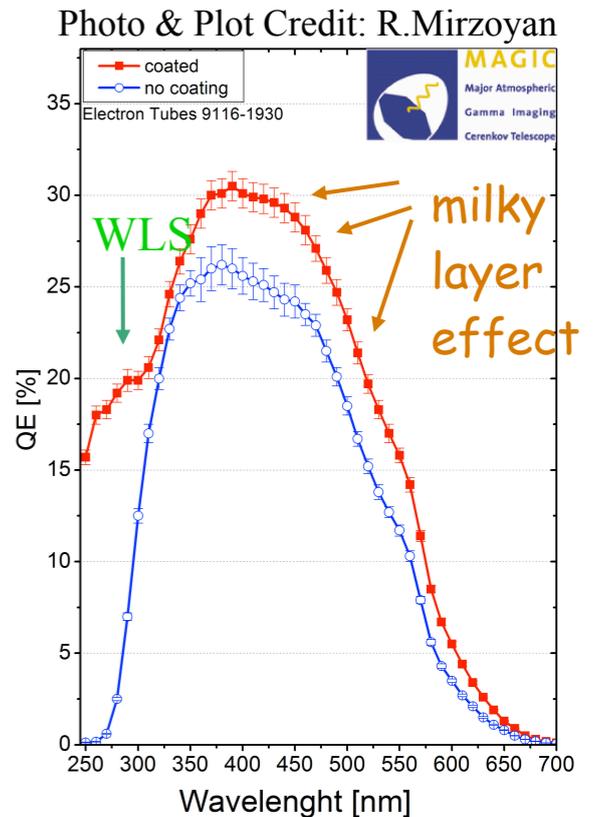
“One-off” Commercial 3” PMT

Development of New Photodetectors, R. Wagner, Argonne, Detector R&D Workshop, 20101008



Improving Photocathode QE

- ▶ High-purity materials
 - reduce scattering from impurities
- ▶ Anti-reflective coating
- ▶ Coating “tricks” →
- ▶ Tune material composition
 - “adjust the recipe ingredients & proportions”
- ▶ Adjust material thickness
- ▶ Use of “under-coatings”
 - MgO
 - Indium-Tin-Oxide (ITO)
- ▶ Novel photocathode materials -- non-alkali metals
 - GaAs
 - GaN
 - GaAsP
 - InGaN



Can we do better than trial & error?

Proposed Argonne Photocathode Growth & Characterization Facility -- A Mid-Future Focus

▶ Scientific Goals:

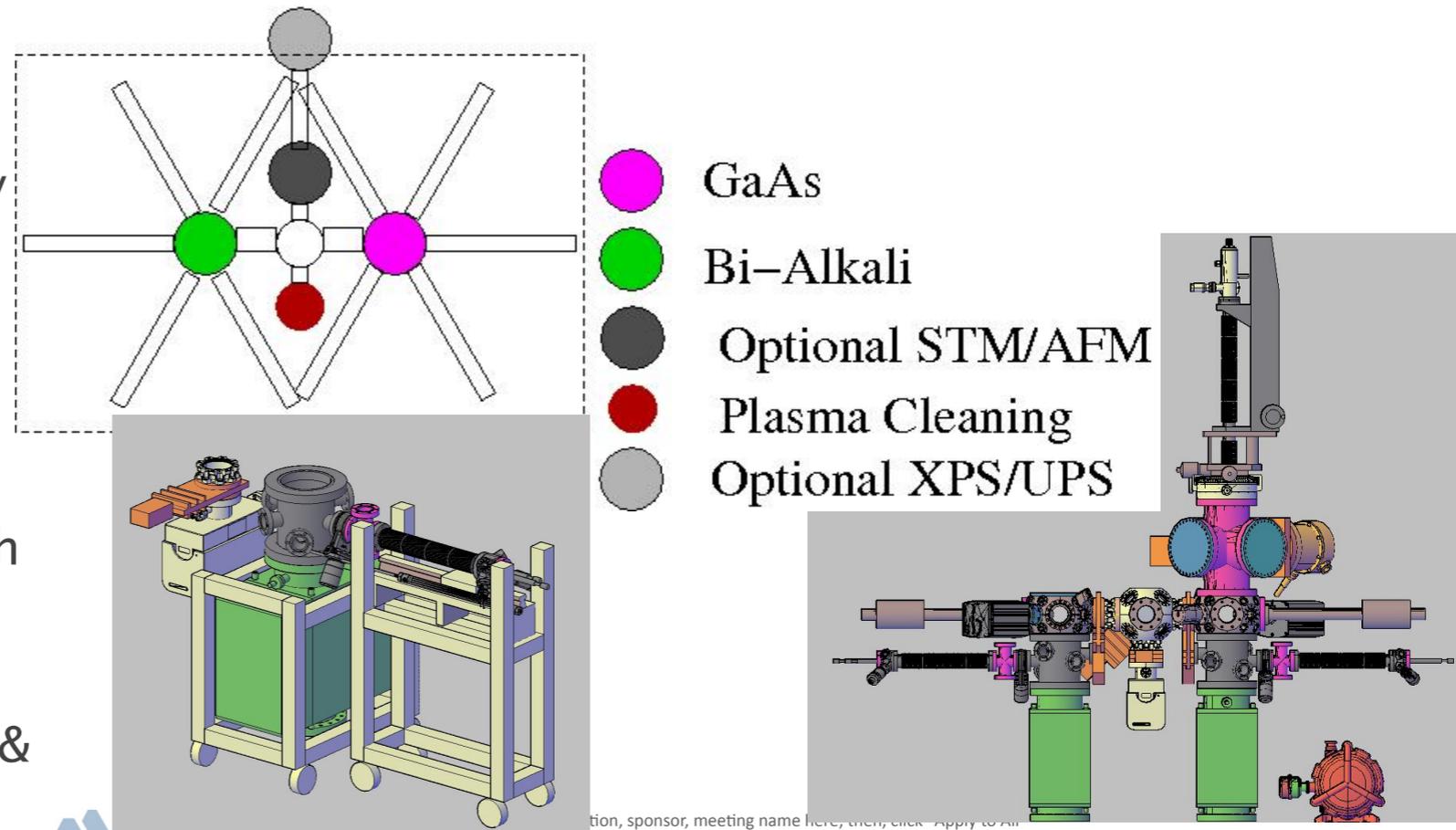
- ▶ Device physics – correlation between structure and functionality of PC
- ▶ Materials Science – microscopic model of growth & activation process
- ▶ Device engineering – reliable high yield growth procedures giving high QE (and low I_{dark})

▶ Engineering Goals:

- ▶ Define process control parameters & acceptable variations
- ▶ Test of process control units

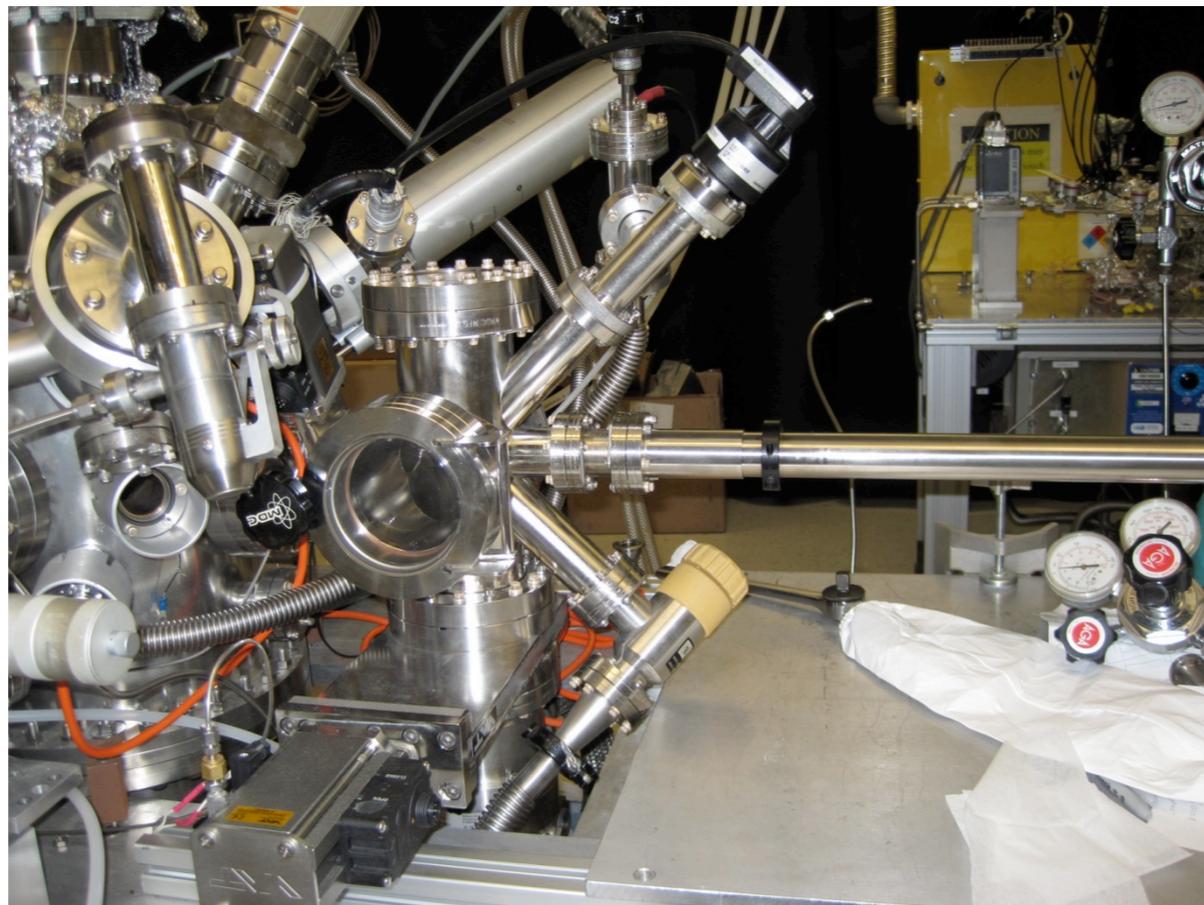
▶ Science Questions:

- ▶ Film structure (chemical phases, crystal orientation, amorphous contribution) & Morphology (roughness, crystal size, surface composition)
- ▶ Influence of substrate on growth characteristics and electronics properties
- ▶ What is best film structure?



Argonne PC Characterization Facility

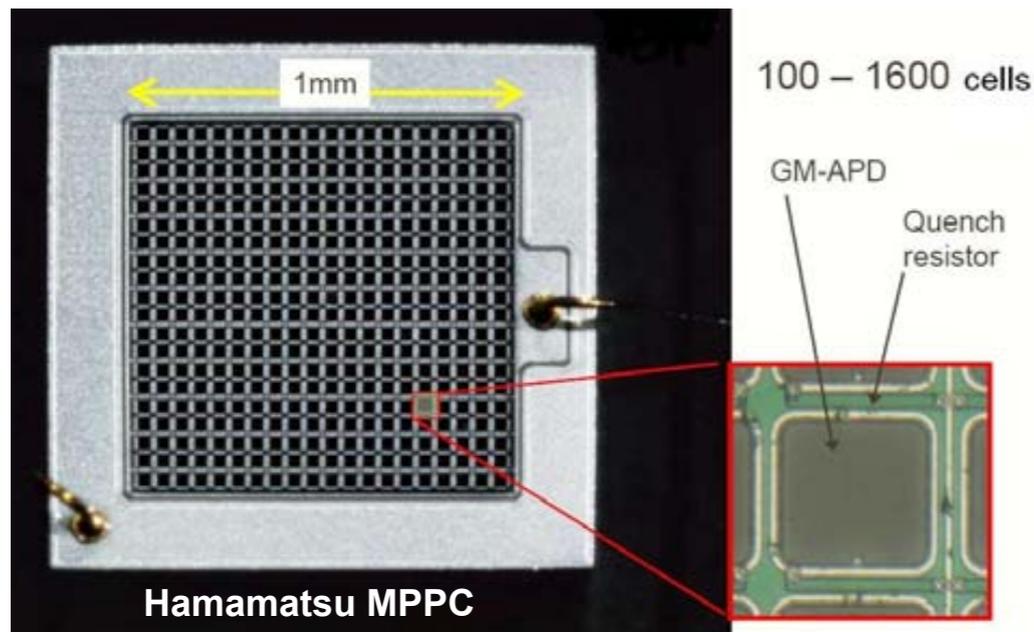
- ▶ Characterization Tools
 - X-ray Photoelectron Spectroscopy
 - UV Photoelectron Spectroscopy
 - Low Energy Electron Diffraction
 - Mass Spectrometer



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Silicon Photomultipliers - G-APD, MPPC, PPD,...

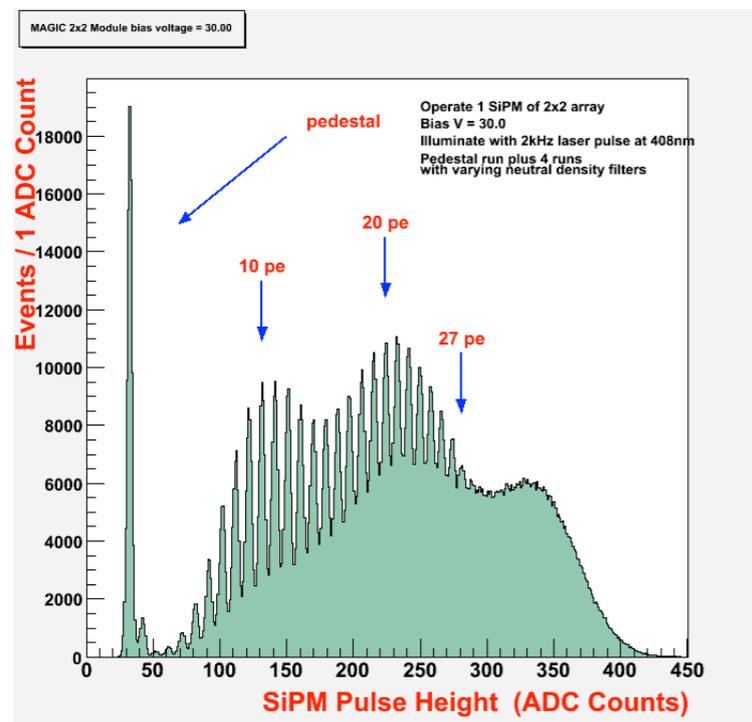


Advantages (compared to conventional photomultipliers:)

- 10^{5-7} gain for low bias voltage (~30-70V)
- Robust: mechanically & exposure to daylight illumination
- Simple biasing & readout -- two pin operation
- Extremely good single photon resolution
- High QE; potentially high overall PDE
- Insensitive to magnetic field
- Small size allows embedding in/on detector
- Good timing resolution (~50-150ps for single PE)

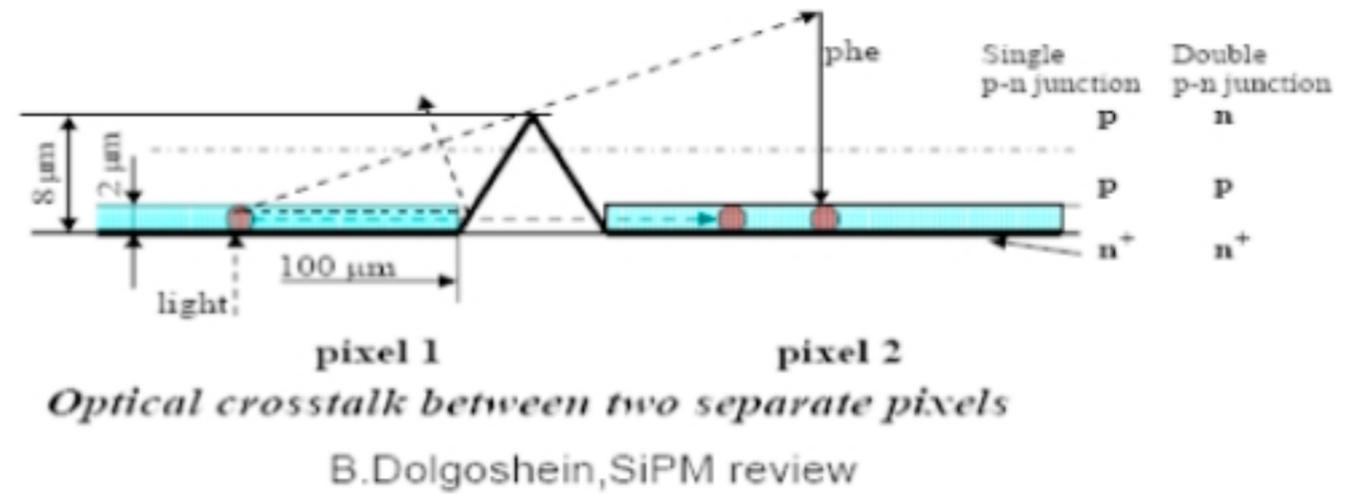
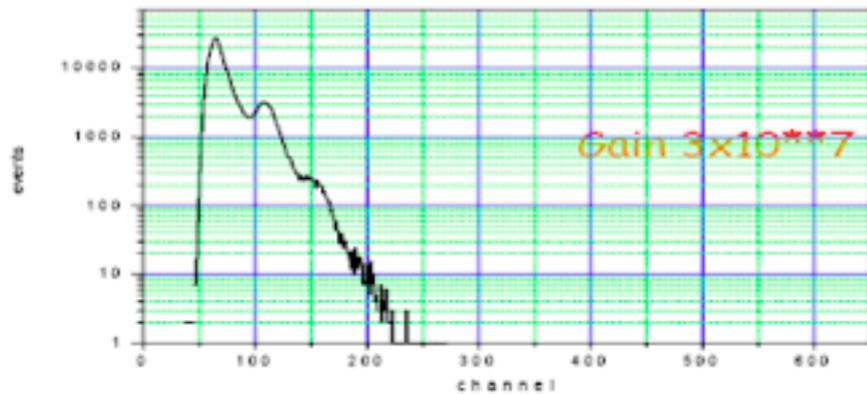
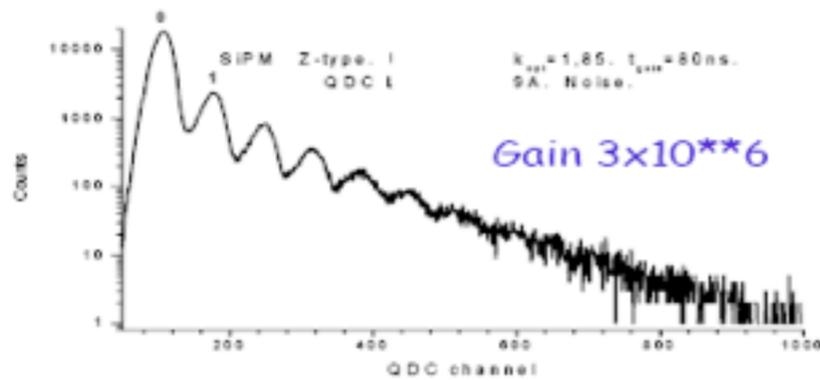
Disadvantages:

- Large noise rate ~few \times 100kHz \rightarrow 1 MHz per 1mm²
- High crosstalk - photons generated in avalanche
- Afterpulsing - charge traps
- Temperature sensitivity of breakdown voltage, noise
- Presently limited to small active area (5 \times 5mm² max.)
- Not particularly radiation hard
- Small operating voltage range



Improved MEPhI SiPM 5x5mm²
with ~1% crosstalk

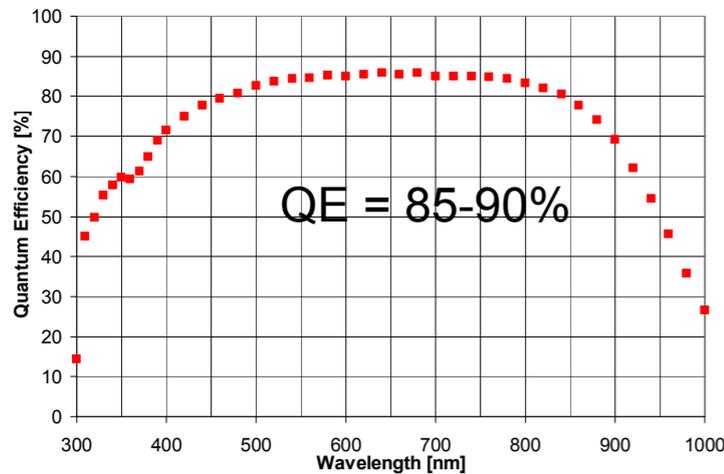
Improving G-APDs



Reduction of crosstalk with
trenching & double p-n junction

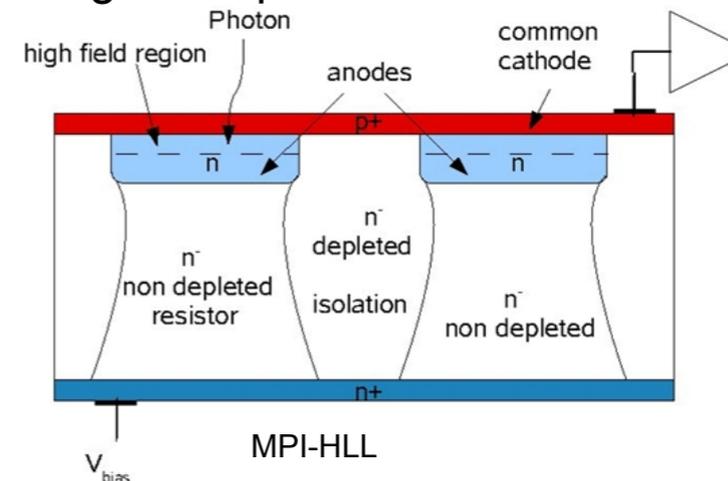
Plot credit: B. Dolgoshein LIGHT06 → R. Mirzoyan, Argonne 2008

$$PDE = QE \times \text{Geom. Eff.} \times P_{\text{breakdown}}$$



Geom. Eff. = 30-70%
depends on pixel size

Improved geometric eff. via
integrated quench resistors



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Future G-APD Improvements - Planned & Desired

- ▶ Larger dynamic range
 - smaller pixel size
 - Zecotek – 15–40k pixels/mm²
- ▶ Larger PDE – improved design
- ▶ Reduced dark count rate – improved materials
- ▶ Larger active area
 - Needed Cherenkov telescope camera application
 - Medical imaging (PET)
- ▶ Improved radiation hardness – new fabrication materials
- ▶ Lower cost
 - We keep expecting this to happen
 - Competition is increasing
- ▶ Integration of G-APD with ASIC (**see Ramburg talk**)
 - active quenching, faster recovery
 - true digital photon counting; now digital→analog→digital

Large Area Picosecond Photodetector Collaboration

The Development of Large-Area Fast Photo-detectors

April 15, 2009

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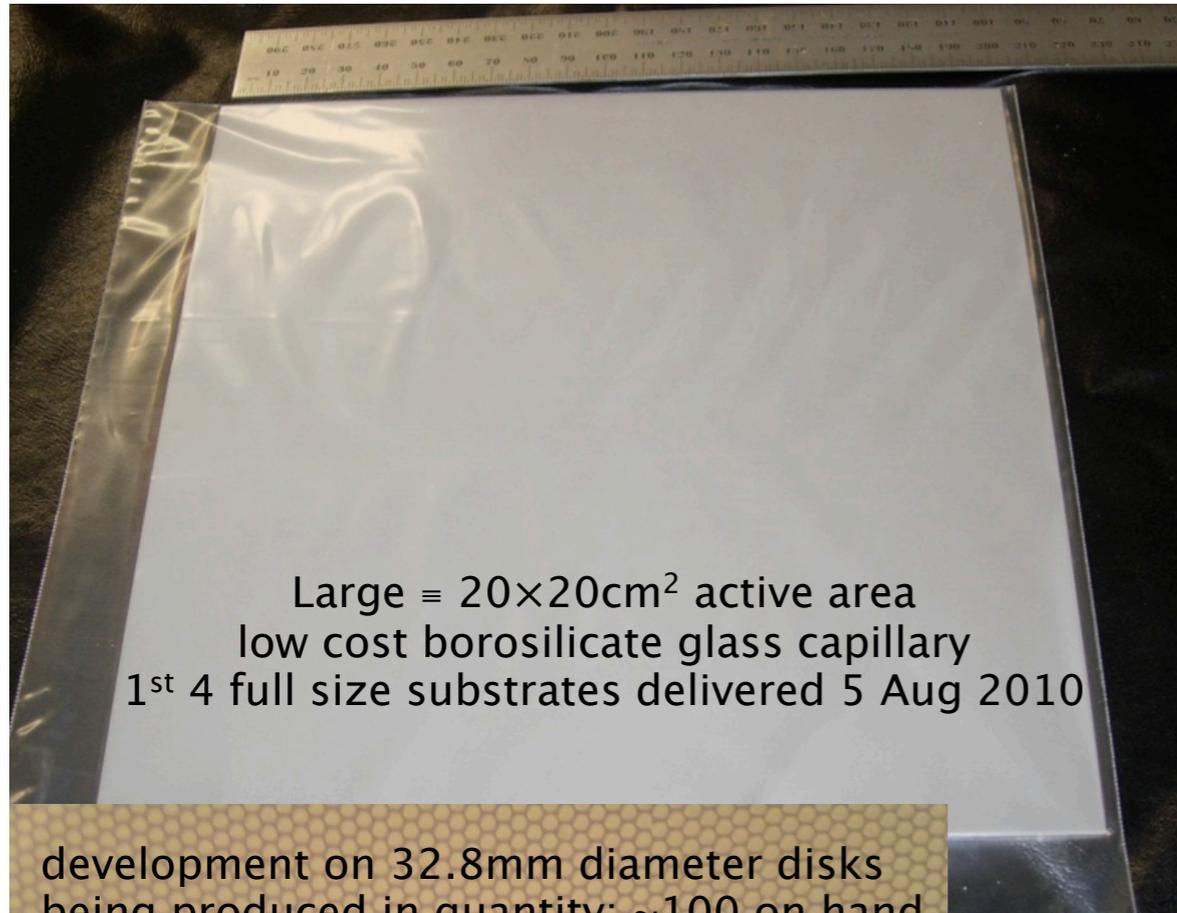
¹ Joint appointment Argonne National Laboratory and Enrico Fermi Institute, University of Chicago

3 National Labs.
6+ Argonne divisions
3 universities
3 small companies

association with
3 universities
2 small companies

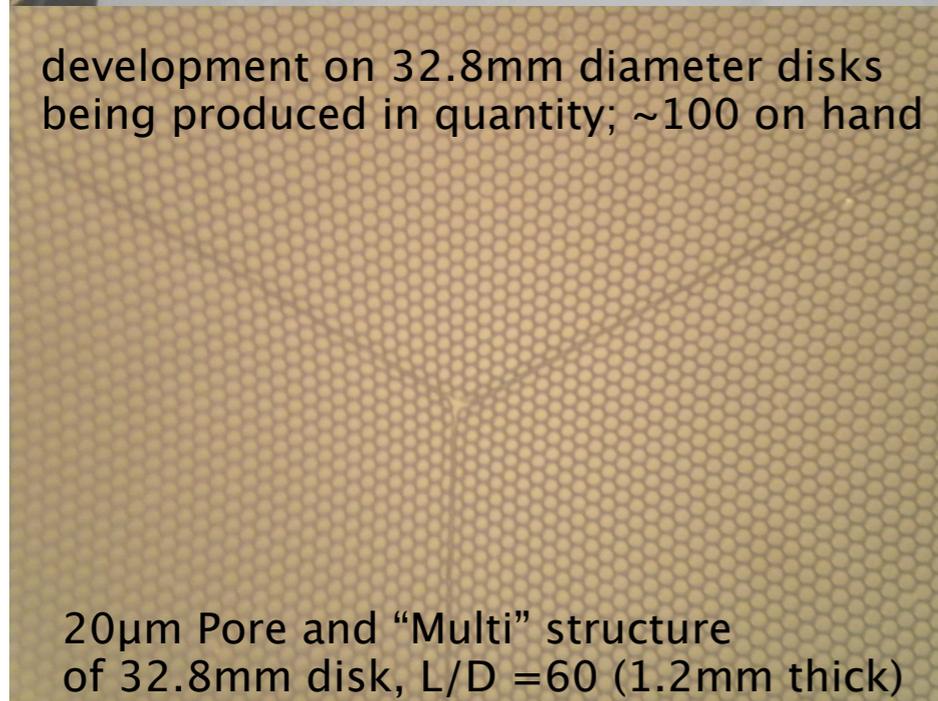
Large Area Picosecond Photodetector Development

Large, Cheap, Fast Microchannel Plate Photomultiplier



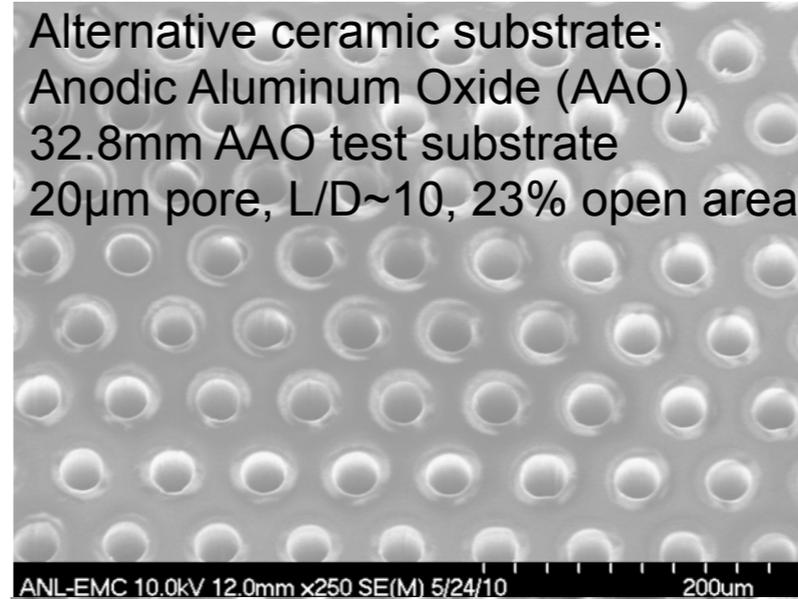
Large \equiv $20 \times 20 \text{cm}^2$ active area
low cost borosilicate glass capillary
1st 4 full size substrates delivered 5 Aug 2010

development on 32.8mm diameter disks
being produced in quantity; ~ 100 on hand



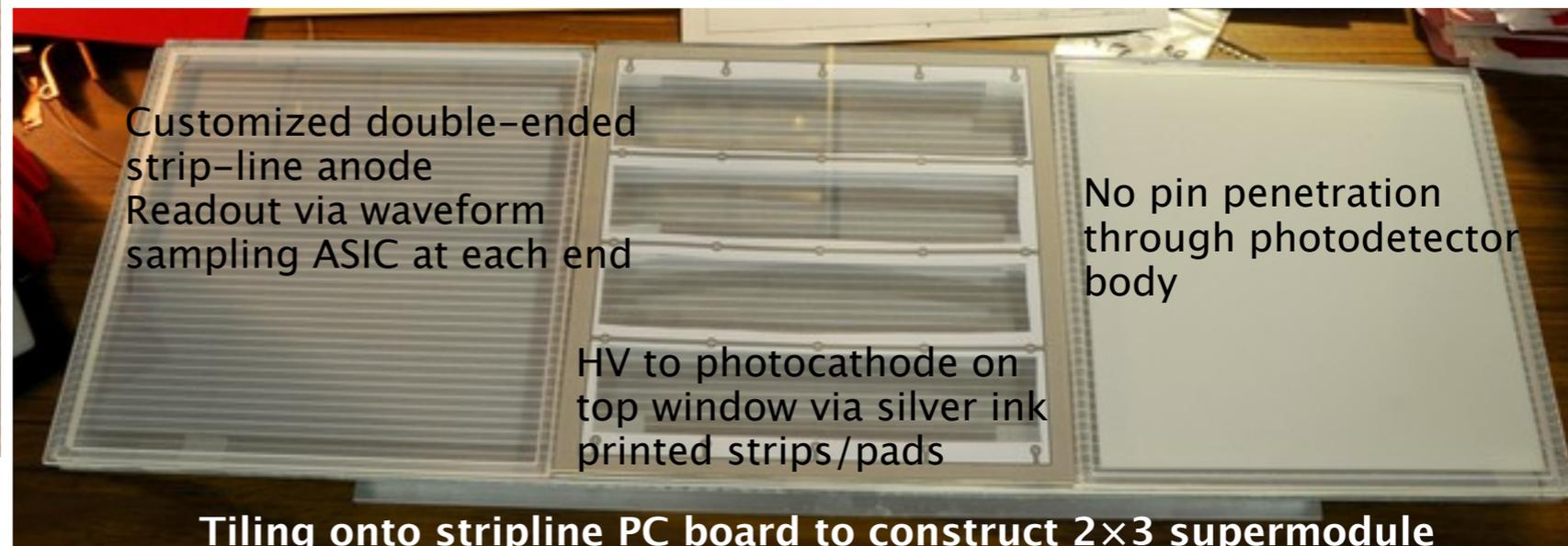
20µm Pore and "Multi" structure
of 32.8mm disk, L/D = 60 (1.2mm thick)

Alternative ceramic substrate:
Anodic Aluminum Oxide (AAO)
32.8mm AAO test substrate
20µm pore, L/D \sim 10, 23% open area



ANL-EMC 10.0kV 12.0mm x250 SE(M) 5/24/10 200µm

- ▶ Pore activation via Atomic Layer Deposition (ALD)
 - Separate material for resistive and secondary emission layers
 - Optimize resistive and emissive properties separately via study of range of materials



Customized double-ended
strip-line anode
Readout via waveform
sampling ASIC at each end

No pin penetration
through photodetector
body

HV to photocathode on
top window via silver ink
printed strips/pads

Tiling onto stripline PC board to construct 2x3 supermodule

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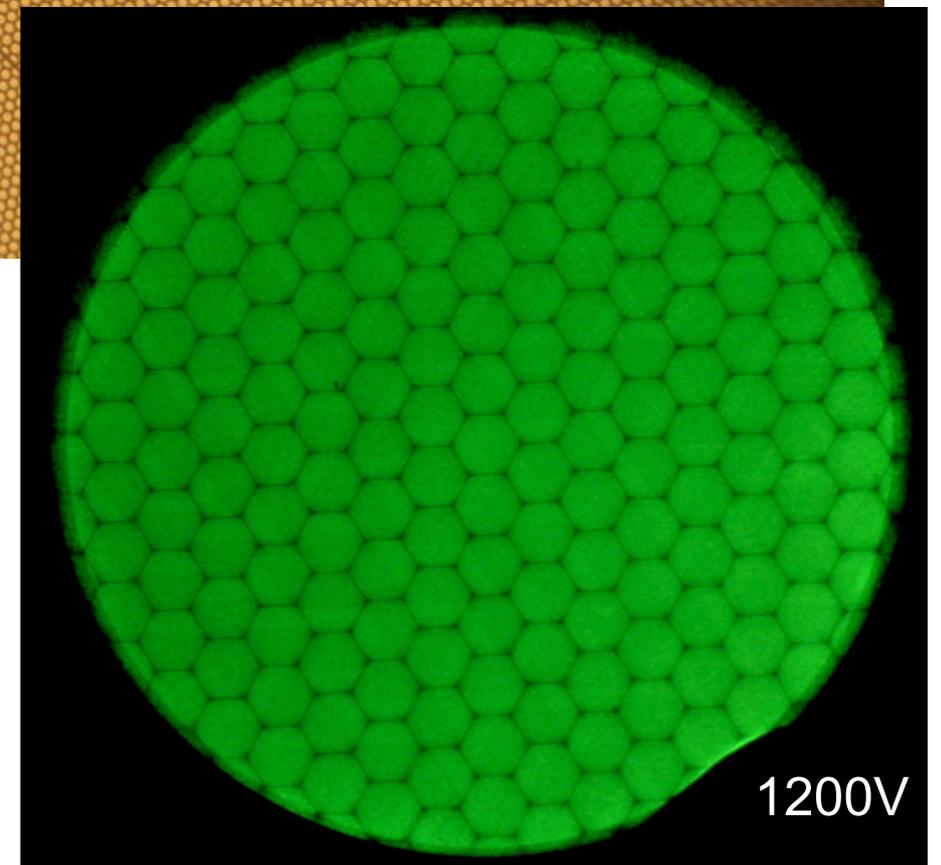
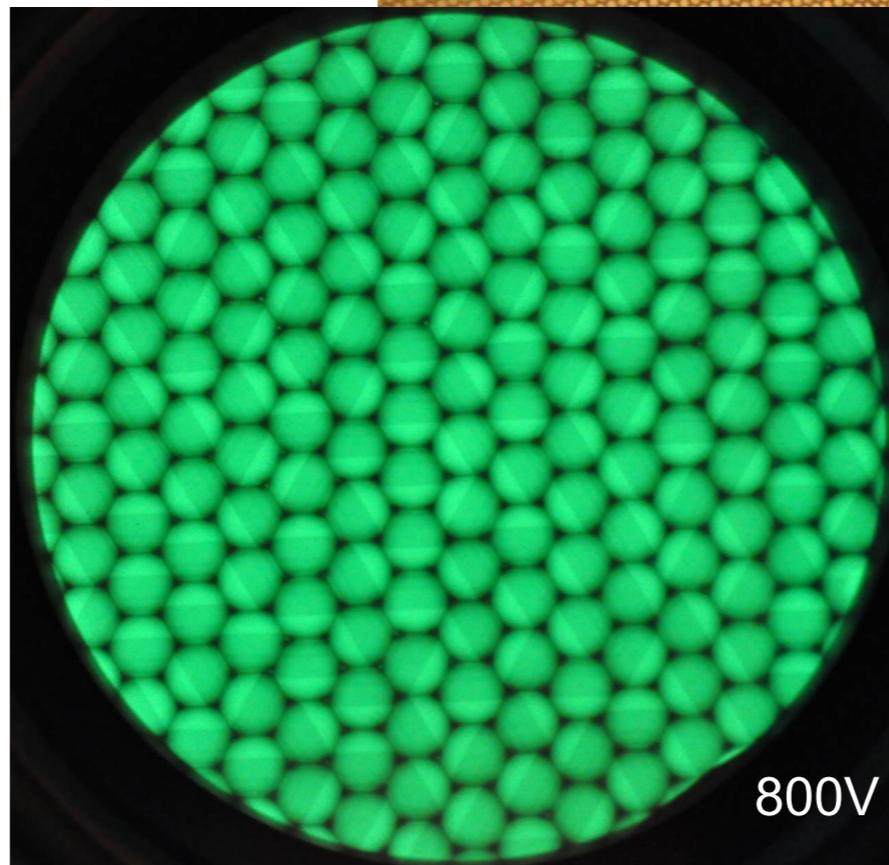
Development of Glass Capillary Arrays

- ▶ Challenges in development of glass capillary arrays
 - drawing – gaps at triple pts.
soln. – larger furnace
 - fusion – distortion of capillaries at “multi” boundaries
soln. – solid core arrays??
 - slice & finish – blocked pores
soln. – keep wet during processing, better post cleaning



GCA-MCP functionalized by Arradance, Inc.
Illuminated with UV lamp and imaged with phosphor screen.

Multi boundaries and triple points apparent. Fade at increased voltage.



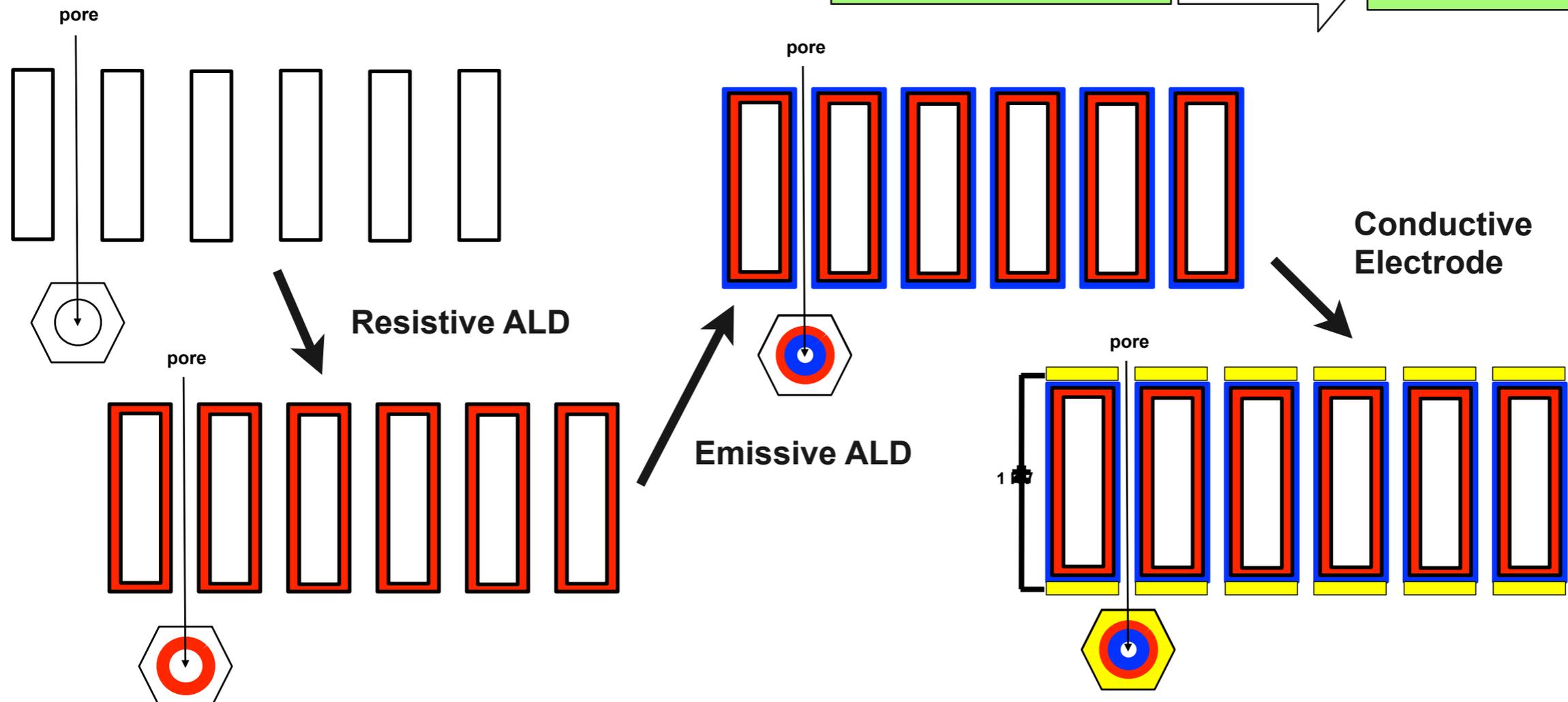
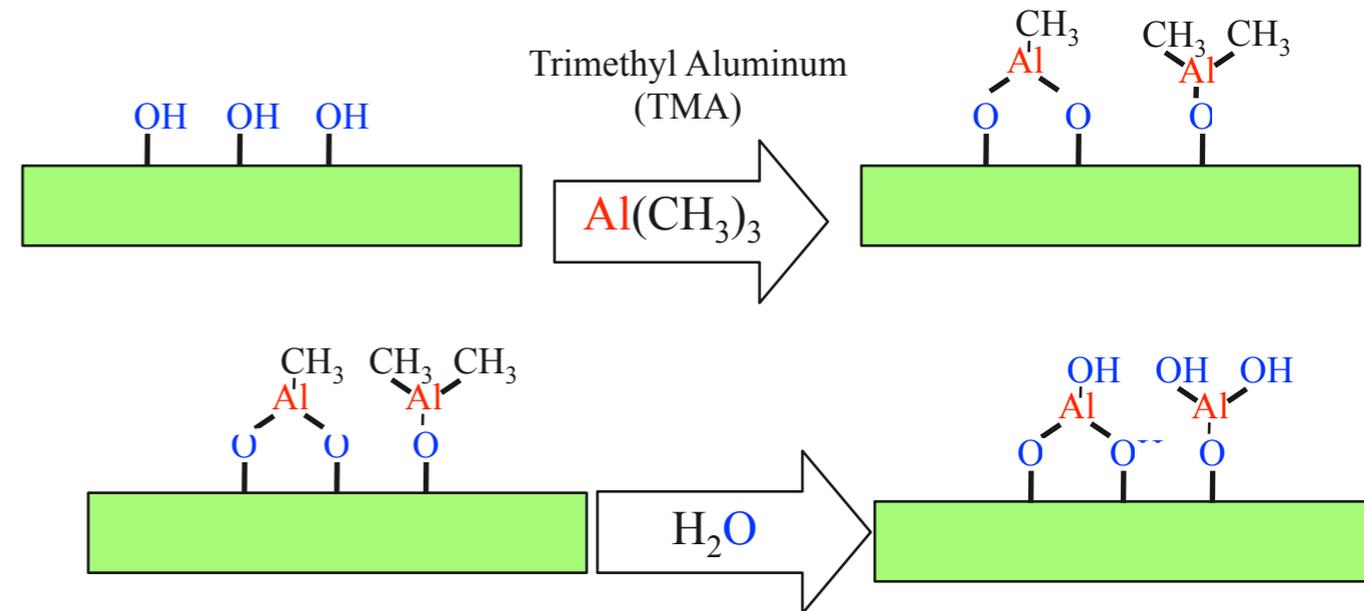
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Pore Activation via Atomic Layer Deposition (ALD)

Example:

- OH on surface provide reaction sites
- Trimethyl aluminum reacts liberating methane, forms Al_2O_3 layer. Leaves methyl group inhibiting further reaction on surface
- Exposure to H_2O removes methyl group. Leaves OH sites for next reaction



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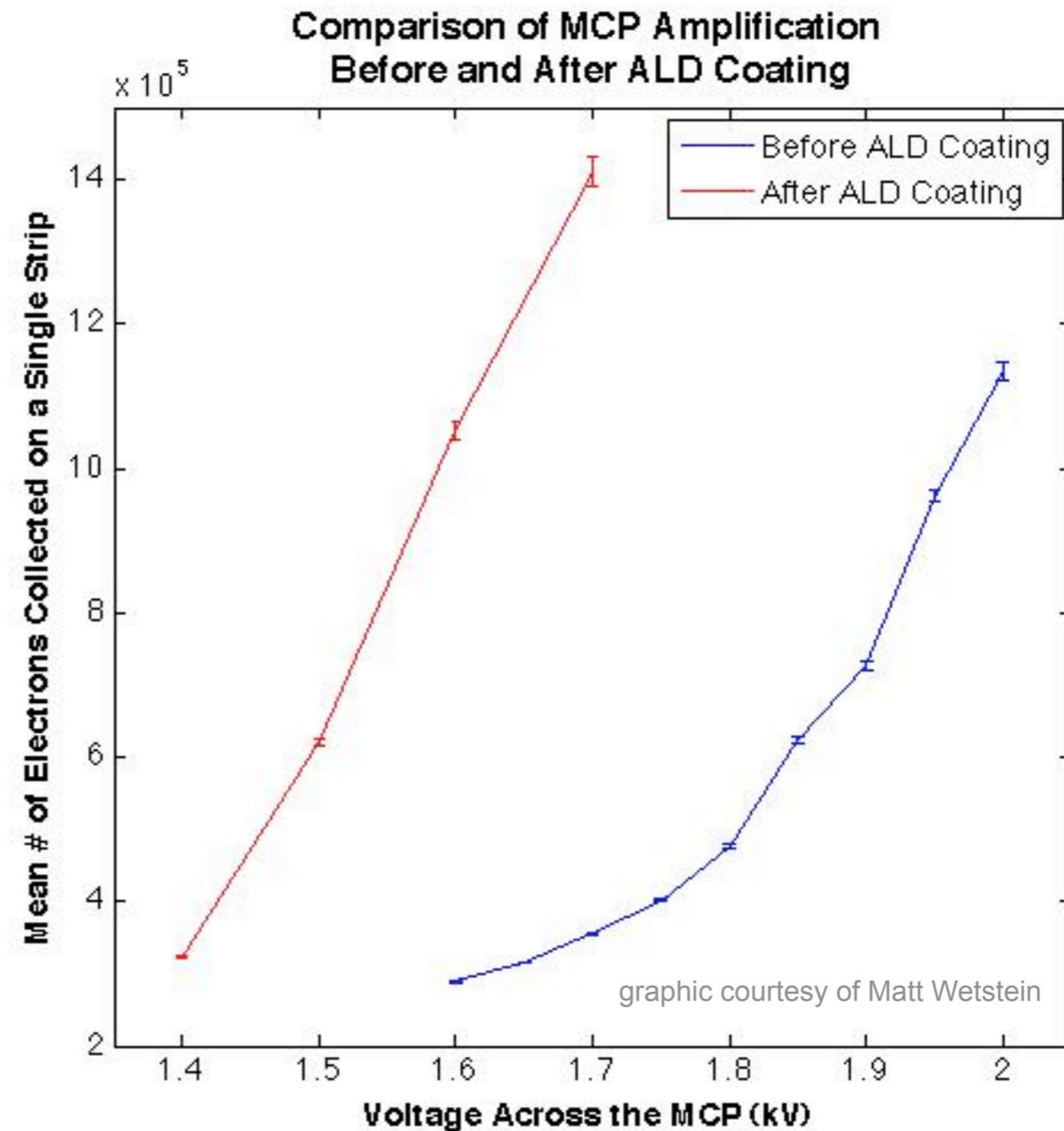


Functionalization of Commercial MCP

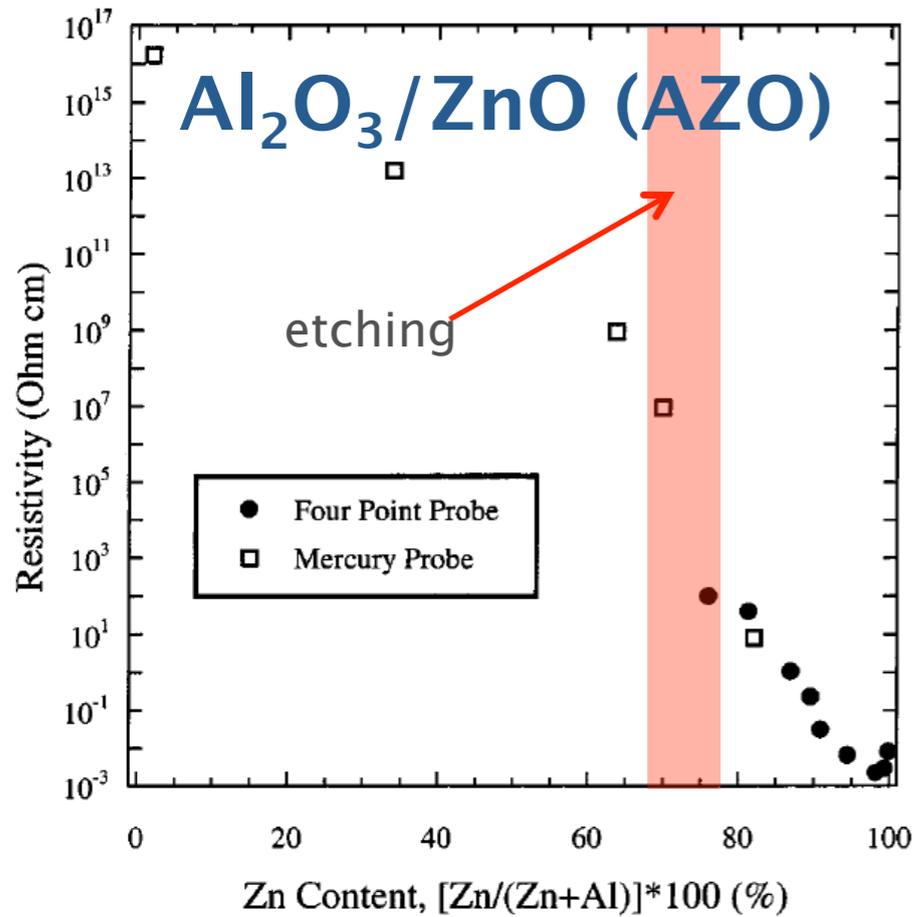
First test of ALD coating

Commercial Pb-Glass MCP
with existing
functionalization

ALD of Al_2O_3 coating
improves gain



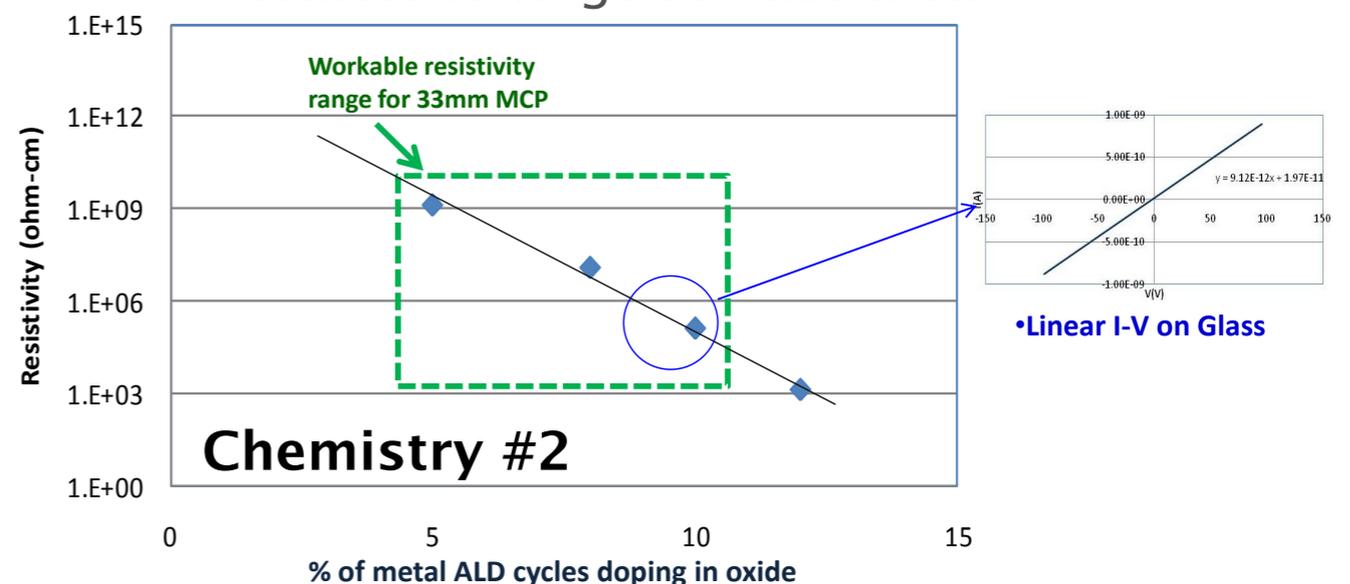
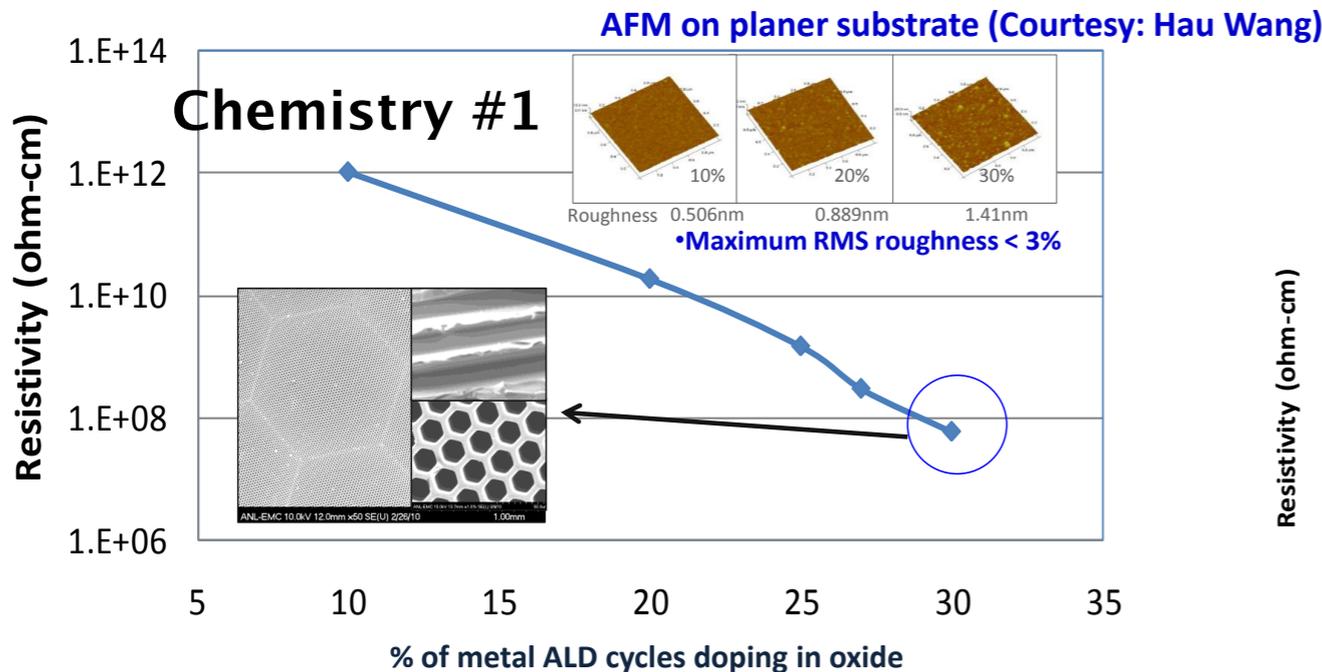
ALD Resistive Coating Development



- First resistive coating tested at Argonne
- Good:
 - Existing process
 - Functionalized MCPs exhibited high gain
- Bad:
 - etching of ZnO by trimethyl aluminum
 - 10⁵ resistance change over 10% composition change

3 Alternative Resistive Chemistries developed by Argonne ALD group

- Good:
 - Good control of resistivity
 - Uniform, smooth coating, no etching
 - Functionalized MCP pair exhibited high gain
 - Scalable to large surface area



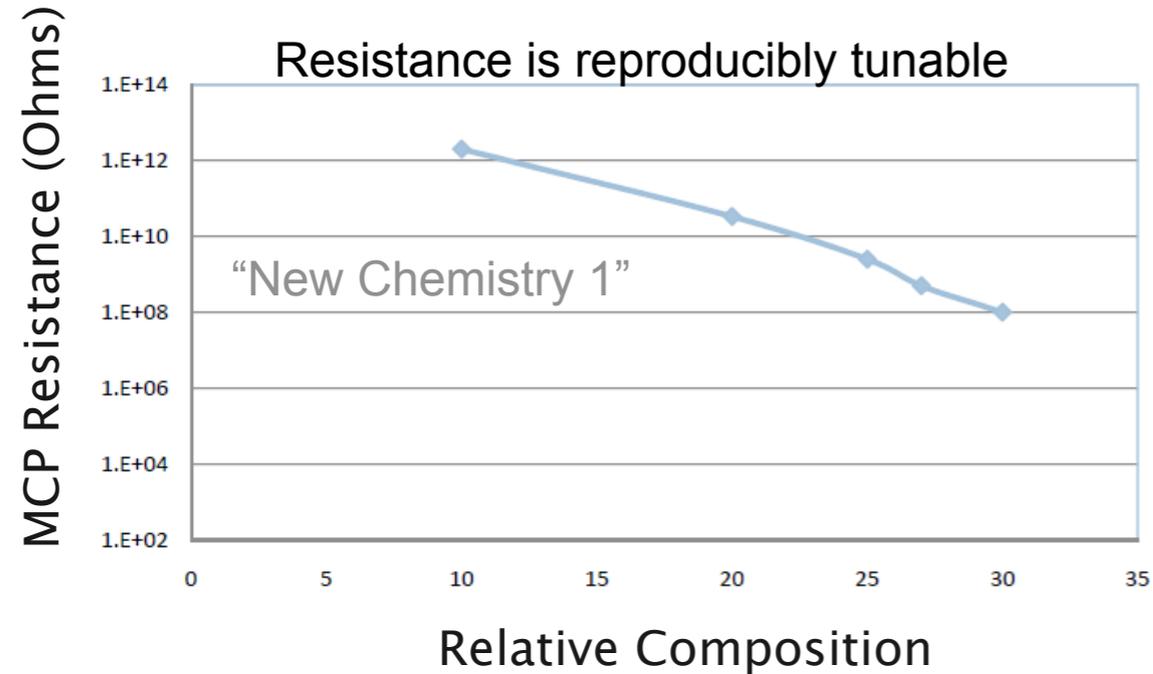
• Uniform and smooth ALD coating pores of MCP

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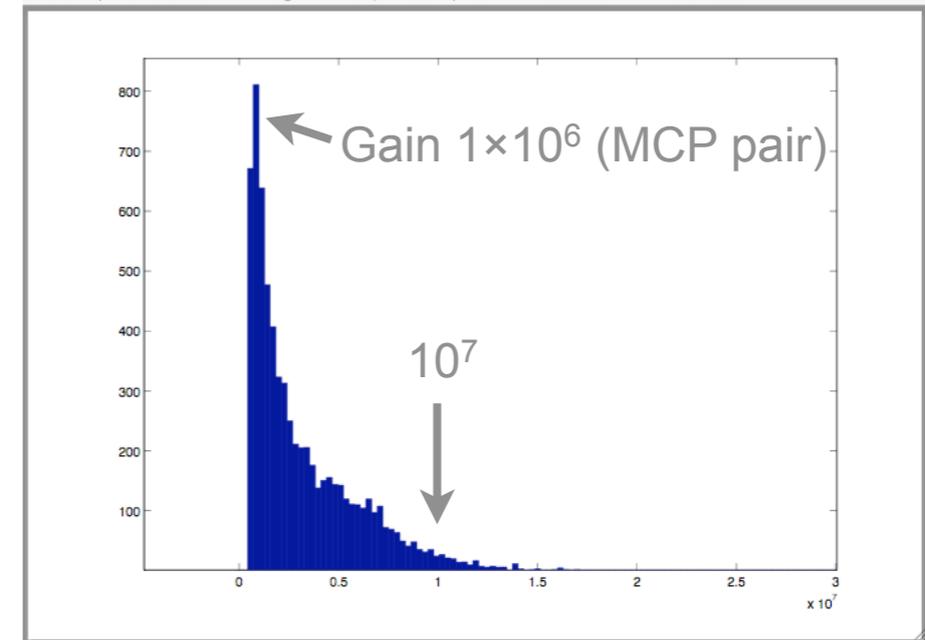


ALD Functionalization of Micro-Channel Plates

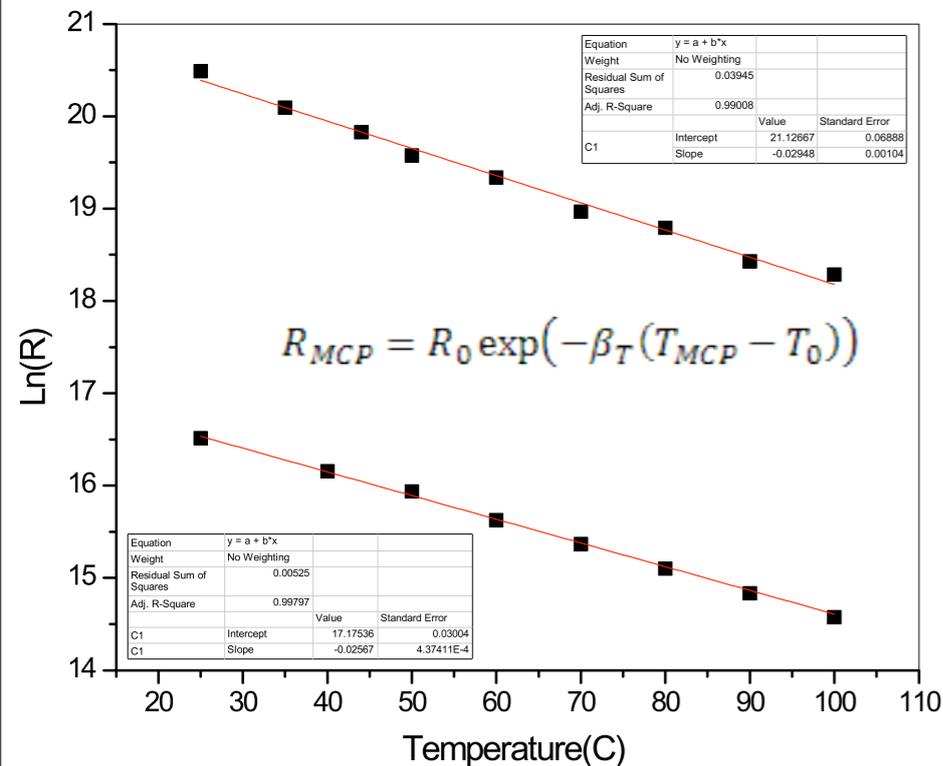
New ALD chemistries for resistive coating developed at Argonne



MCP 72/78 Amplification: 1.3/1.2 kV

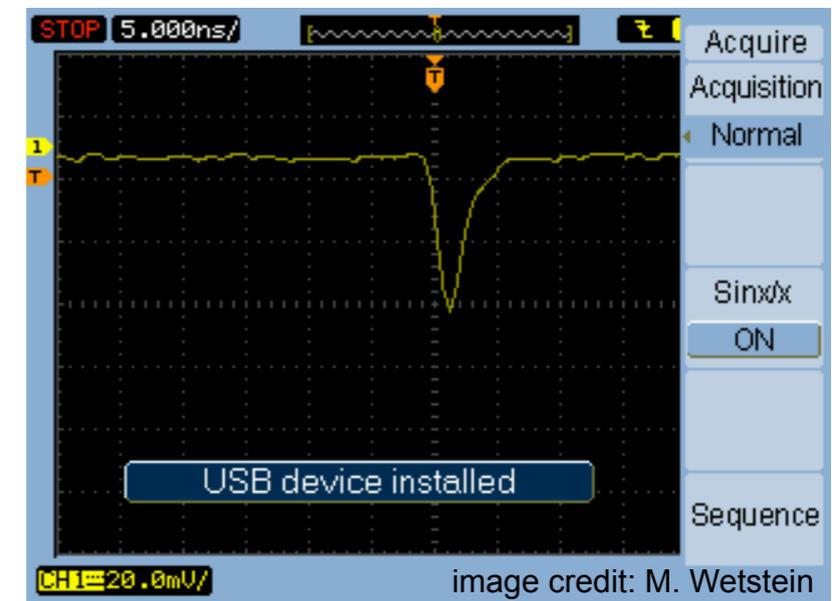


Al₂O₃ Secondary Emission Layer



$\beta_T = -0.02$ for commercial MCP (literature)
 $= -0.027$ “New Chemistry 1”

$$R_{MCP} = R_0 \exp(-\beta_T (T_{MCP} - T_0))$$



Signal from MCP pair coated with new resistive layer + Al₂O₃ emissive layer

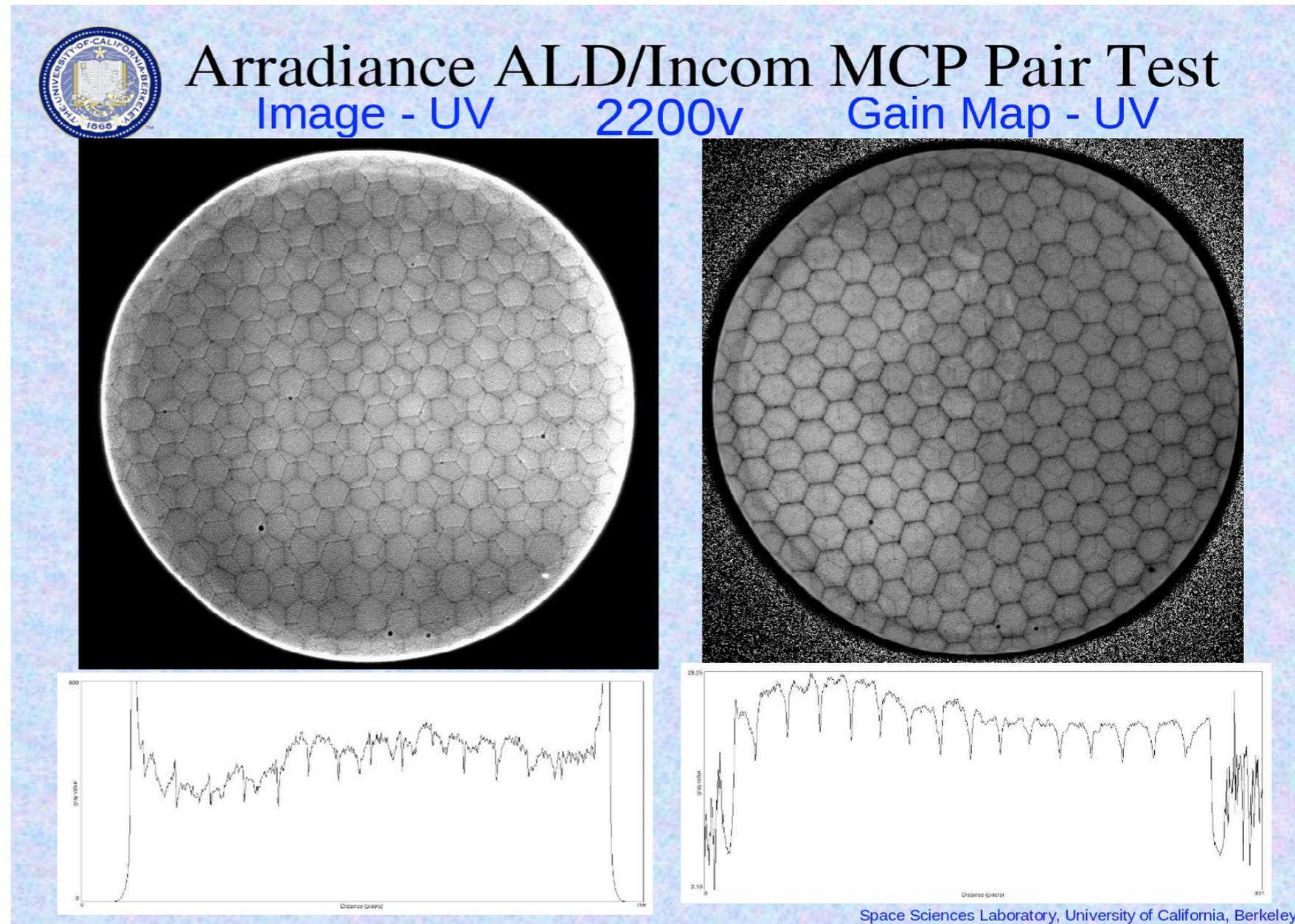
Visual Study of ALD Coated MCP

Glass capillaries coated by Arradance, Inc.

Pair test at Space Sciences Lab/UC-Berkeley

Electron map of MCP

“Multi” boundaries visible, fade at higher gain

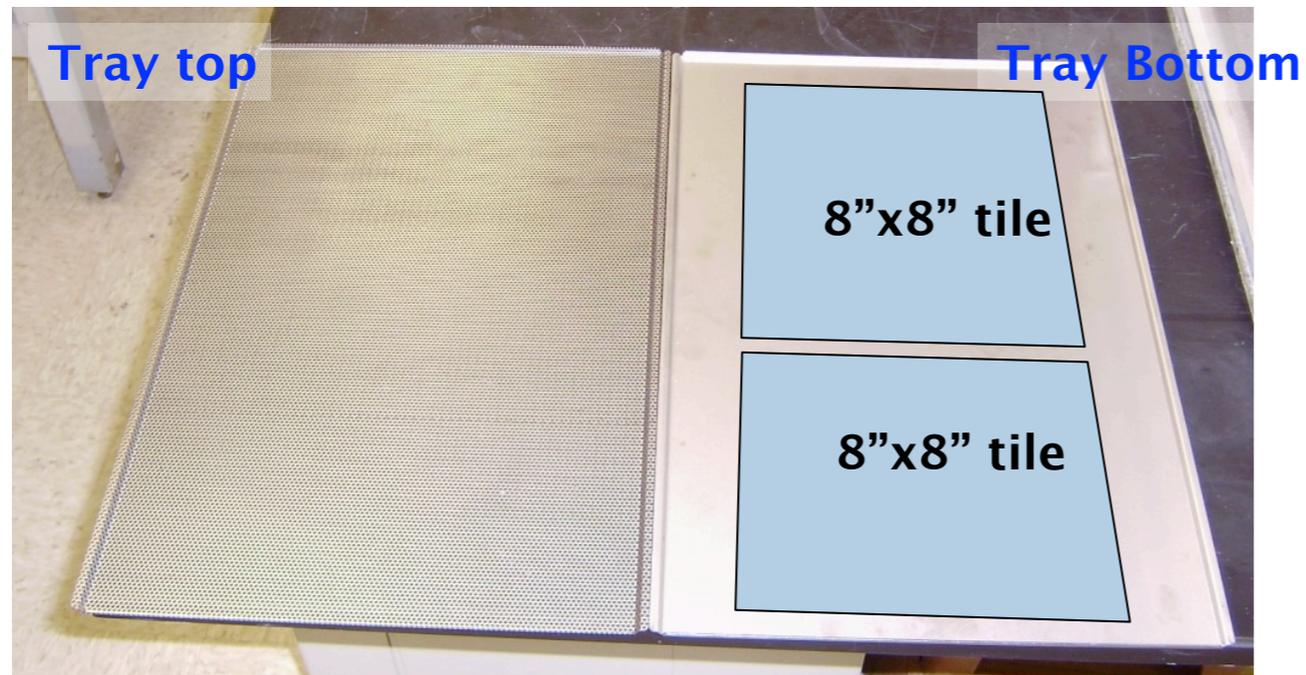


Scale-Up of ALD Processing -- Beneq Reactor

Arrived 18 May 2010

Studying ALD on Large Surface Areas

- 33mm disk surface area is 0.13m^2
- 8"x8" surface area is 6.4m^2
- 20 MCPs area is 129m^2

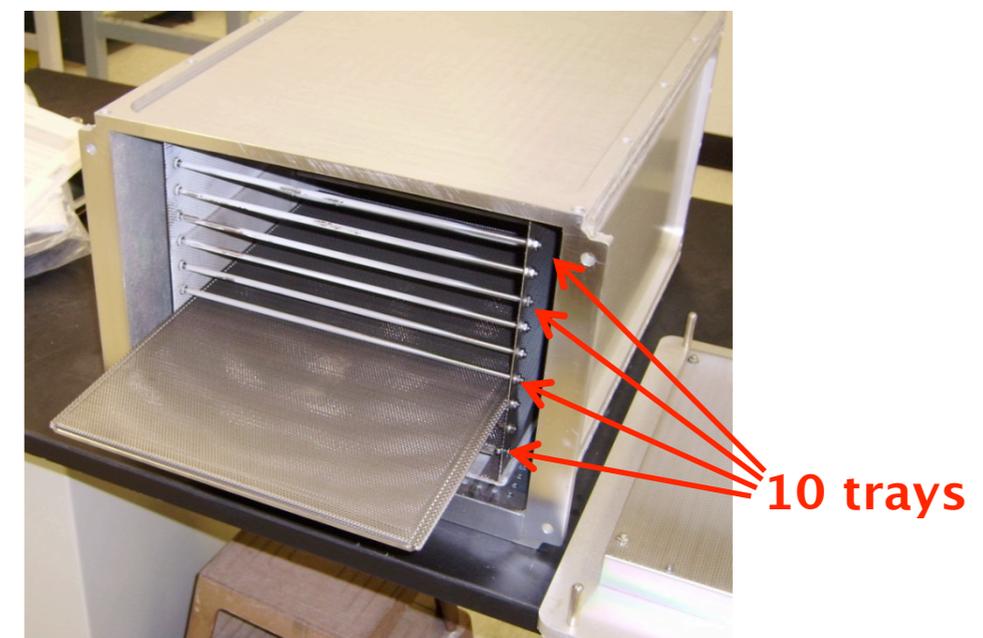
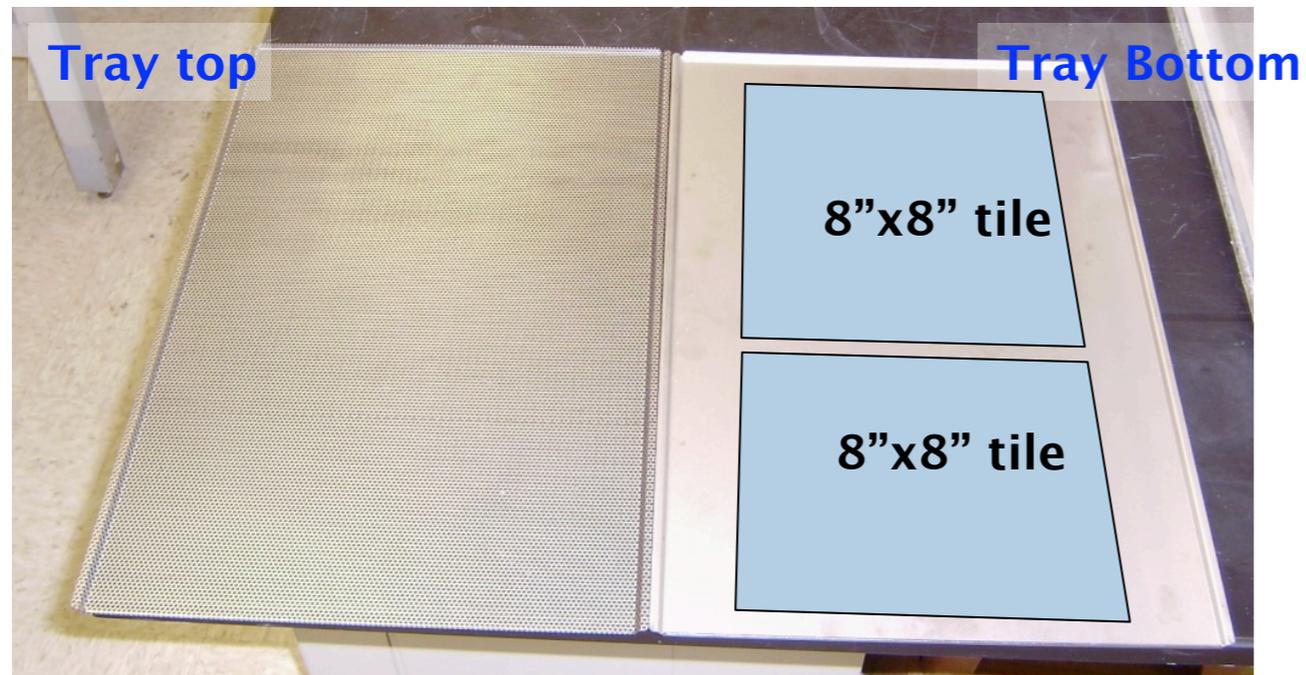


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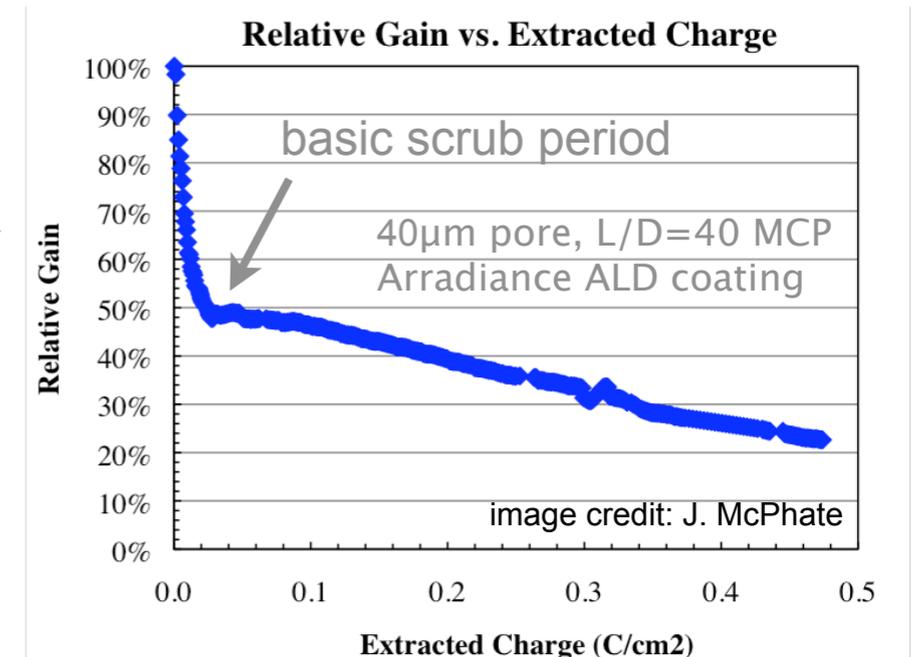
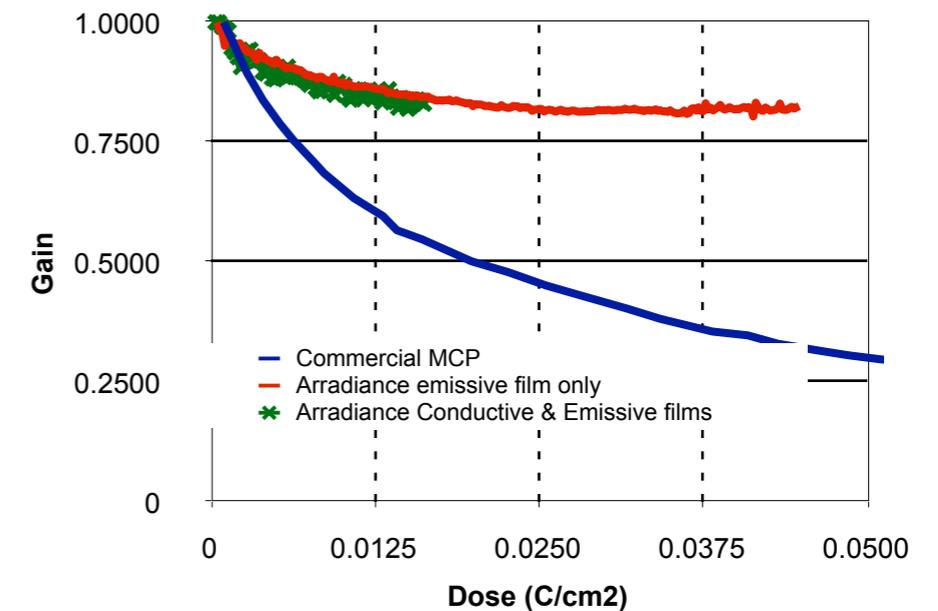
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Advantages of ALD vs Conventional Pb Glass MCP

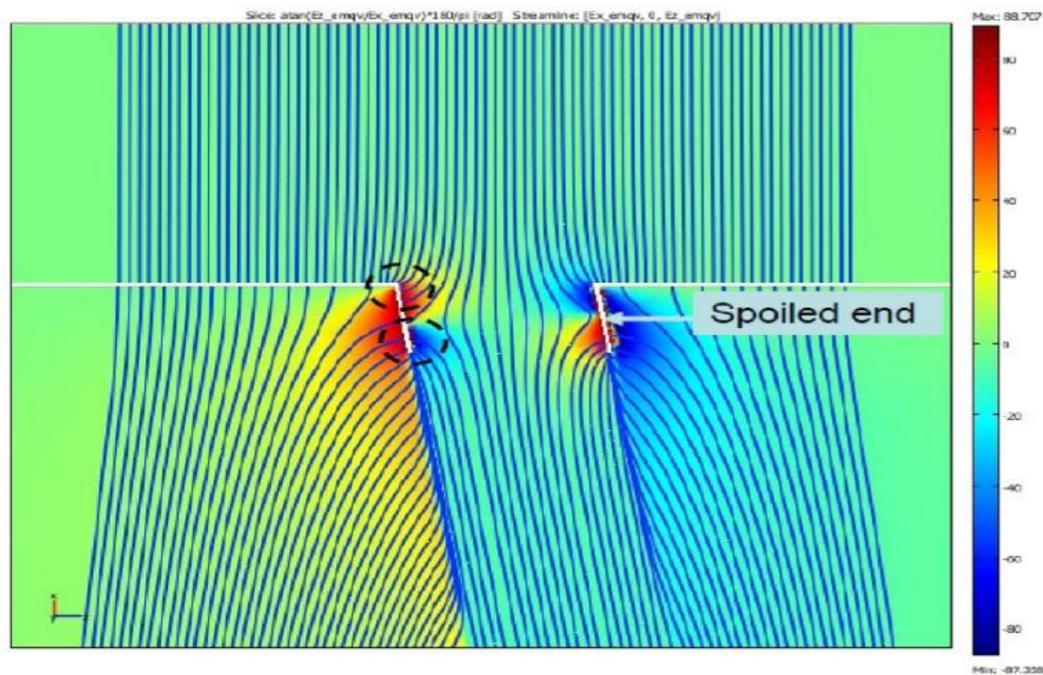
- Conventional lead-oxide MCPs have single composition for resistive/emissive material
 - Functionalized in H-furnace requiring long “scrubbing” time (removal of volatiles)
- ALD allows separate control of resistive and emissive layers
 - separately optimize each layer for best overall performance
 - Scrub time reduced by up to $\times 10$

Arradiance, Inc.



Simulation of MCP & Material Performance

Spoiled end. Color: field angle



Trajectories

MCP size:
Diameter = 25 μm
Length = 1000 μm
Aspect ratio 40

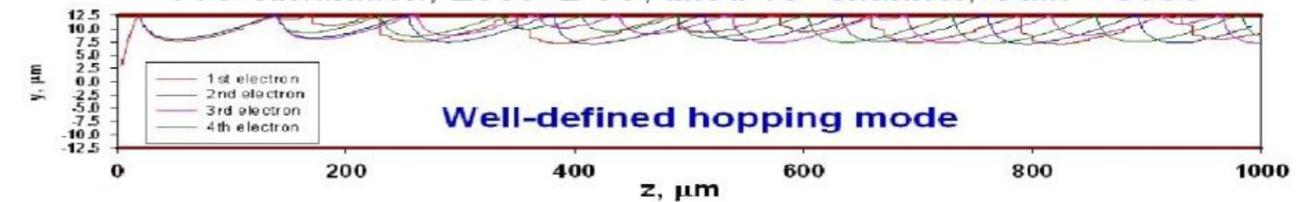
TTS simulation, $E_{\text{sec}}=2$ eV, direct channel, Gain = 14



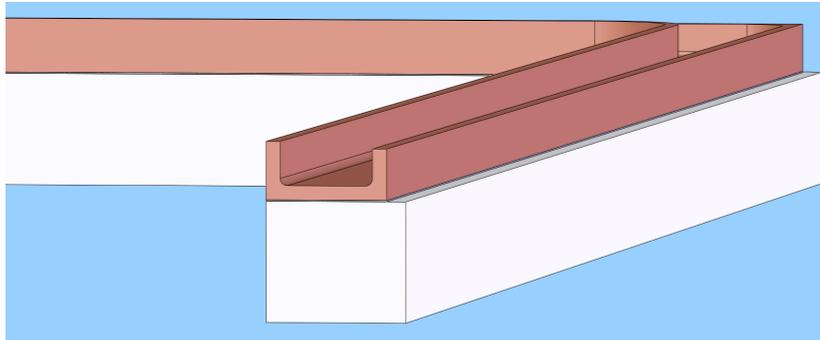
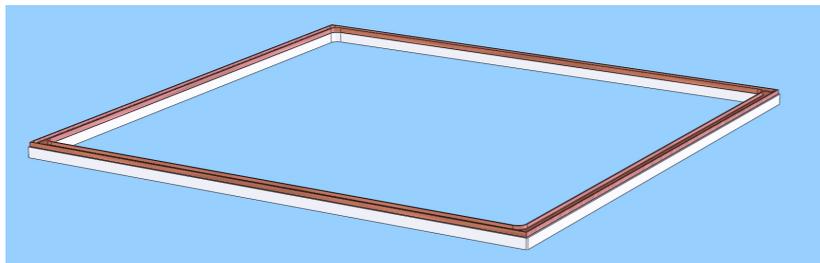
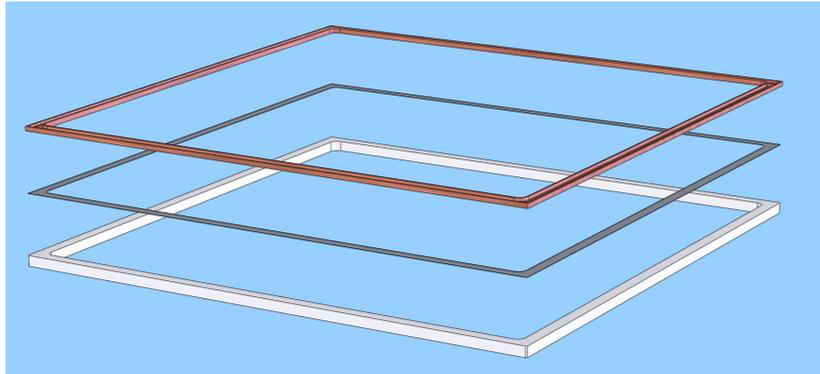
TTS simulation, $E_{\text{sec}}=2$ eV, tilted 7.5° , Gain = 143



TTS simulation, $E_{\text{sec}}=2$ eV, tilted 10° channel, Gain = 3730

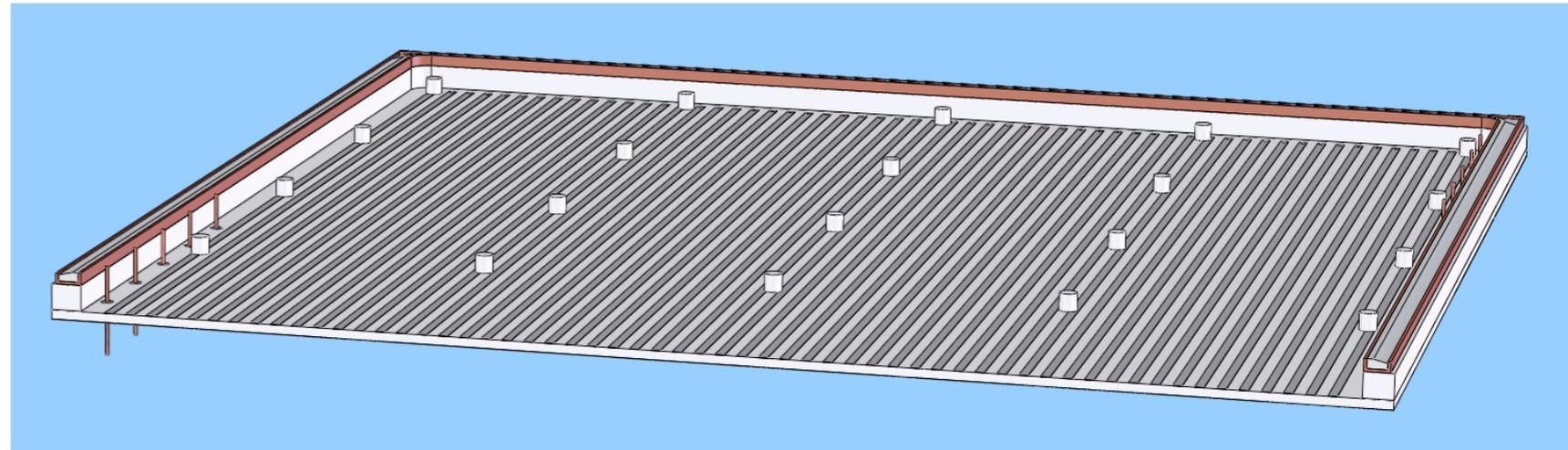


MCP Photomultiplier Packaging -- Ceramic Body (Space Science Laboratory/UC-Berkeley)

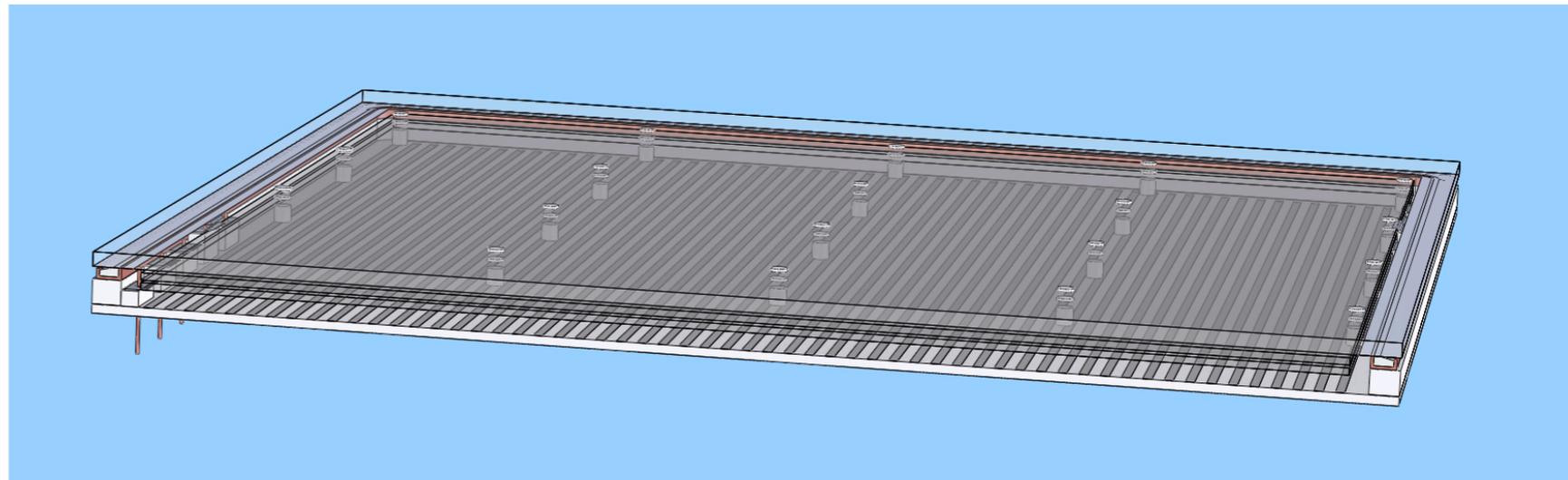


Single Joint Brazed Body
Tray for Indium top seal

- Kovar
- Ni plated/sintered
- Cu plated for Indium wetting



SSL/UC-Berkeley Ceramic Body Design

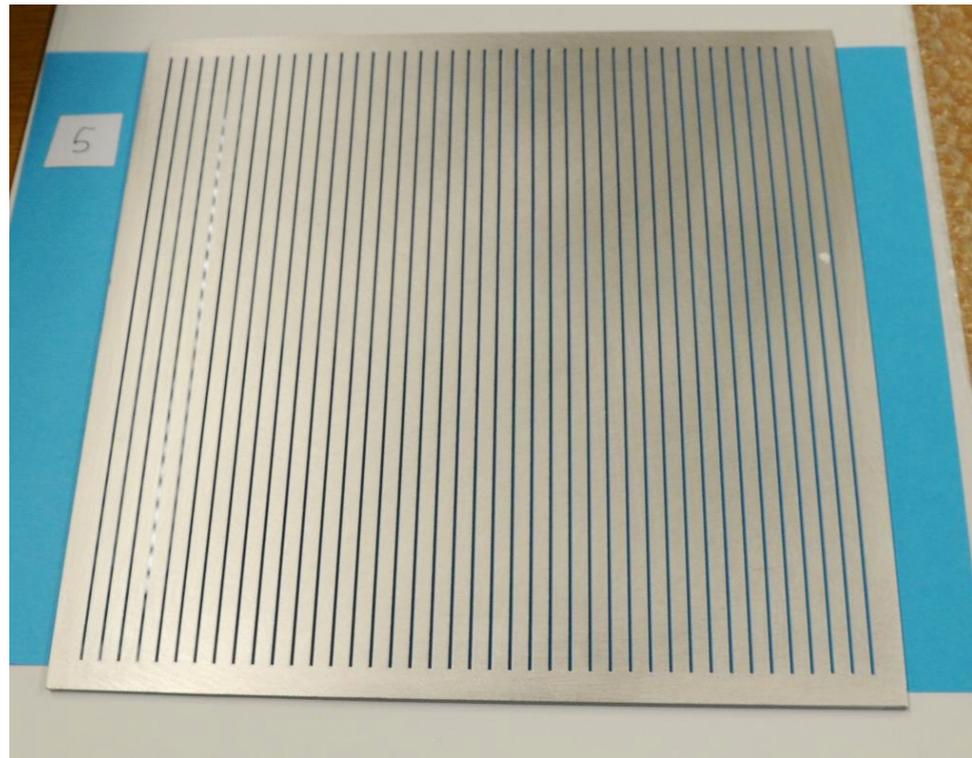


Final assembly with MCP, photocathode
top plate, anode strip line, HV pins

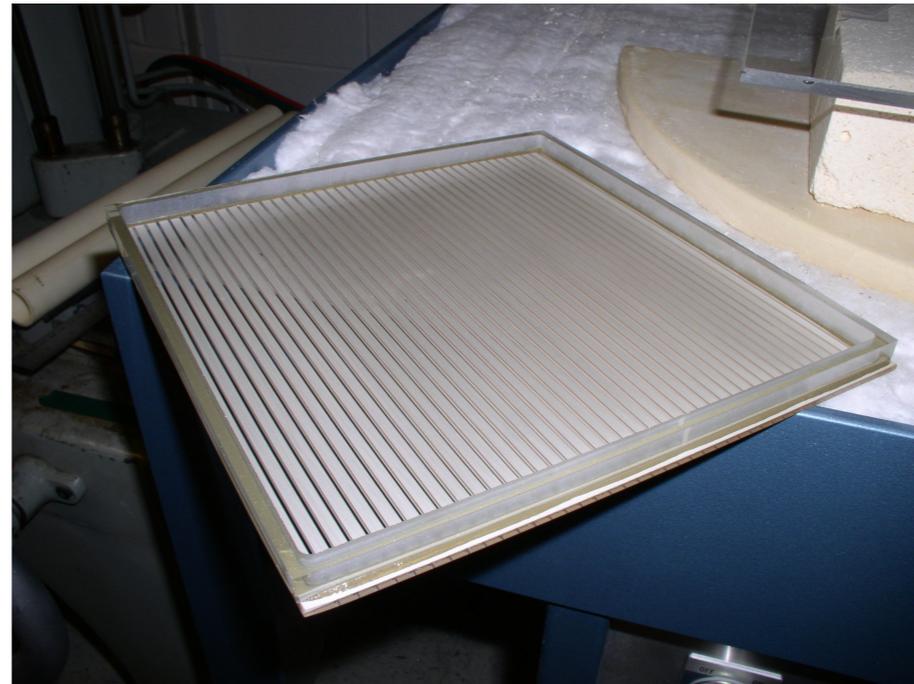
MCP Photomultiplier Packaging -- Borofloat Glass Body (Univ. of Chicago/Argonne Natl. Lab.)

Ceramic body is proven method. Design by SSL group with years of experience.
Relatively expensive.

UC/Argonne alternative design with inexpensive glass & bonding methods. Untested.



Silk-screen printing of anode ground plane on B33 glass



Sidewall bonded to bottom plate with glass frit

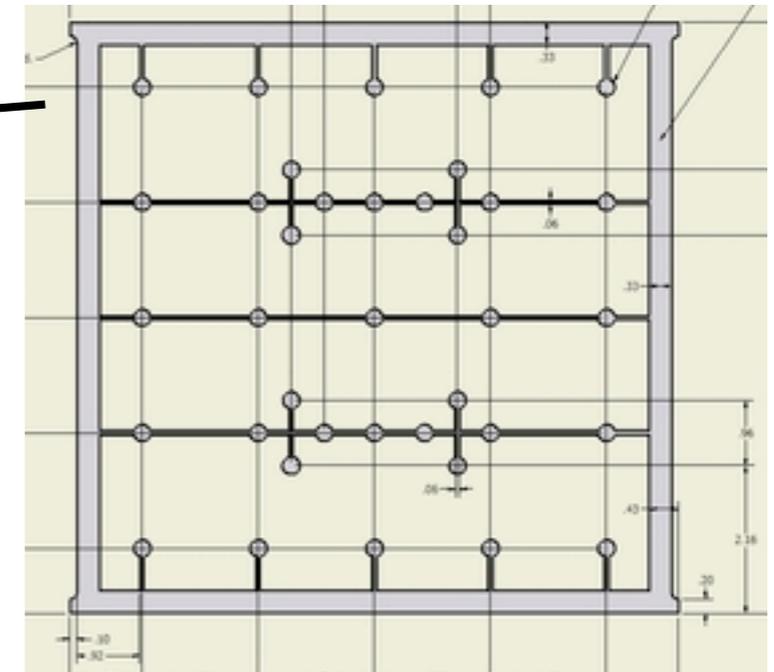
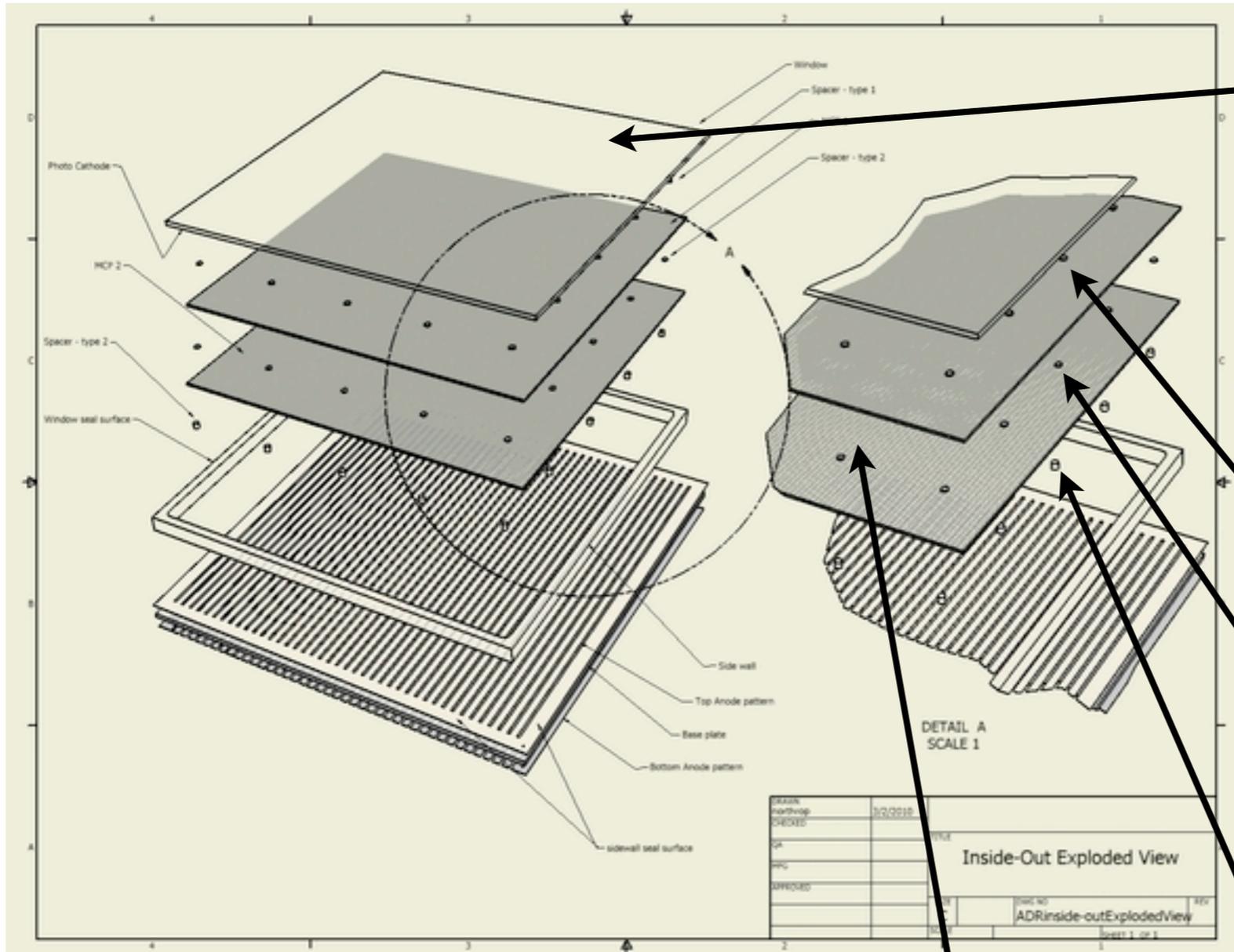
First "sealed box". No internals.
Glass "drop piece" for internal support.
Top seal is glass frit in this test.
Will ultimately use Indium or Indium alloy



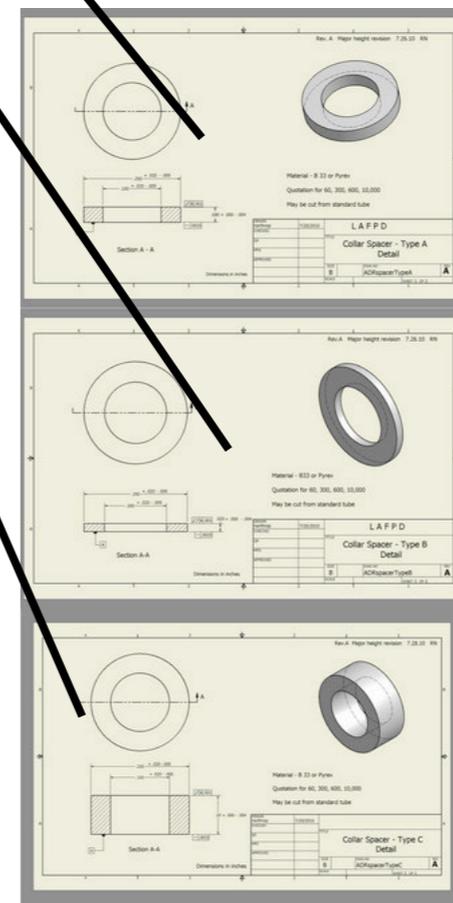
Development of New Photodetectors, R. Wagner, Argonne, Detector R&D Workshop, 20101008



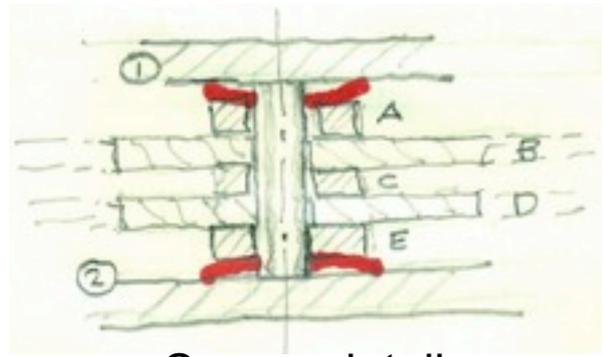
Mechanical Assembly of Tiles -- Overview



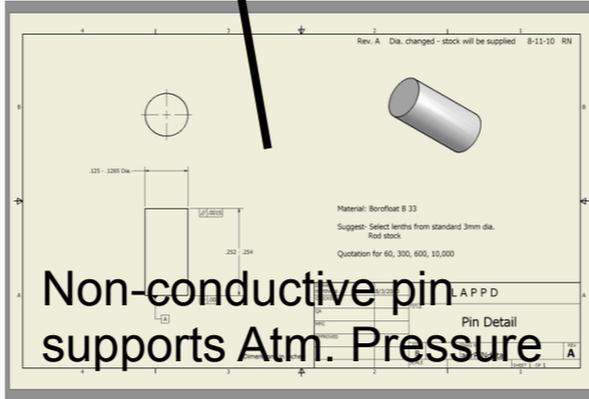
Photocathode Top Window
HV distribution through strip pattern



Conductive spacer collars set HV distribution through MCPs & to anode ground



Spacer detail



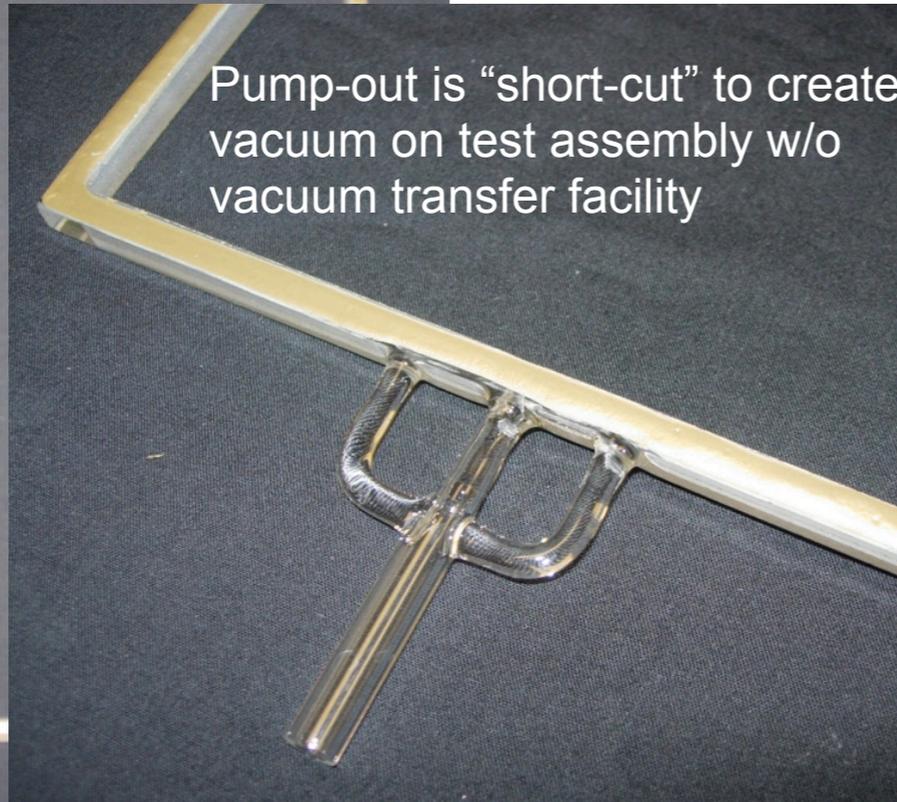
Non-conductive pin supports Atm. Pressure

Development of New Photodetectors, R. Wagner, Argonne, Detector R&D Workshop, 20101008



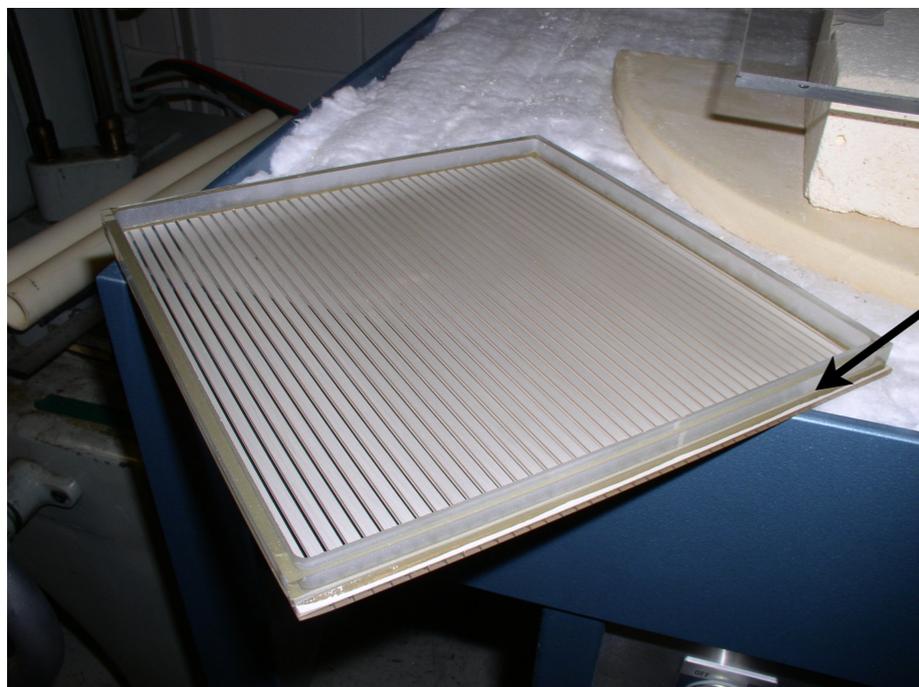
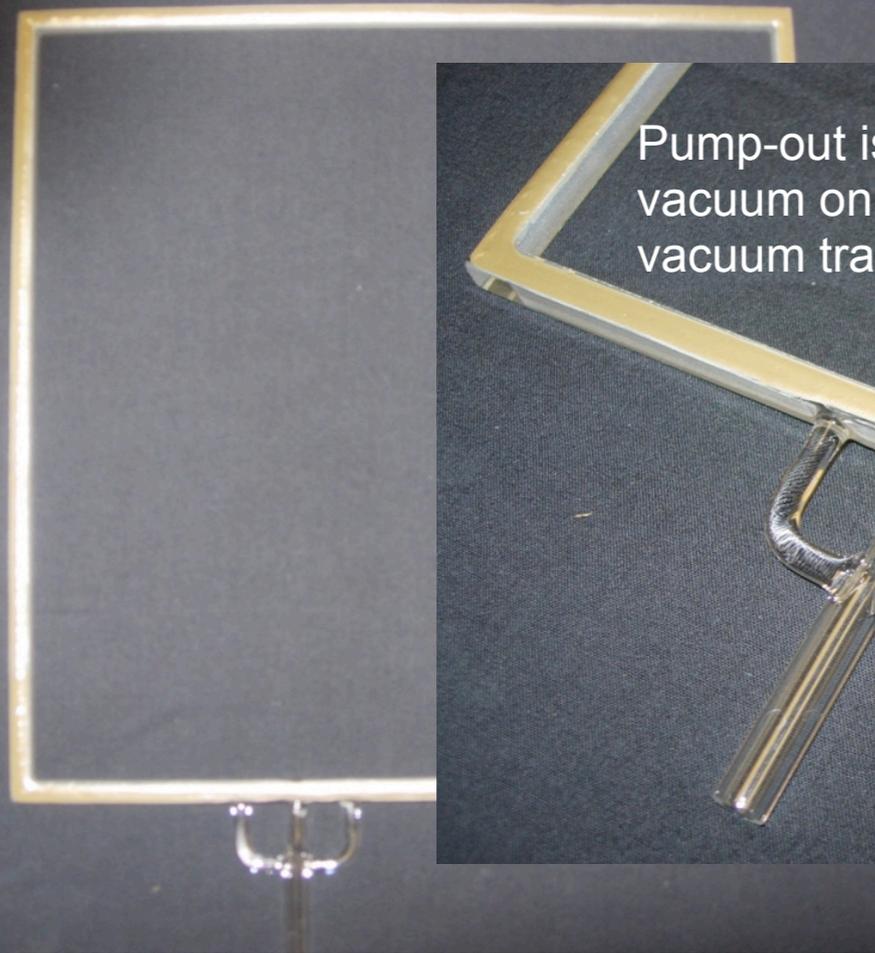
Tile Base Assembly -- Anode Bottom Plate & Sidewall

- Develop technique to reproducibly bond sidewall to bottom anode plate
 - Center sidewall frame w.r.t. bottom plate; 2 sides flush, equal overhang on anode ground strips



Sidewall bonds along thin silver strip
Extension of strip past sidewall for bridging grounds between tiles

An arrow points from this text to the bottom edge of the tile assembly shown in the bottom-left image.

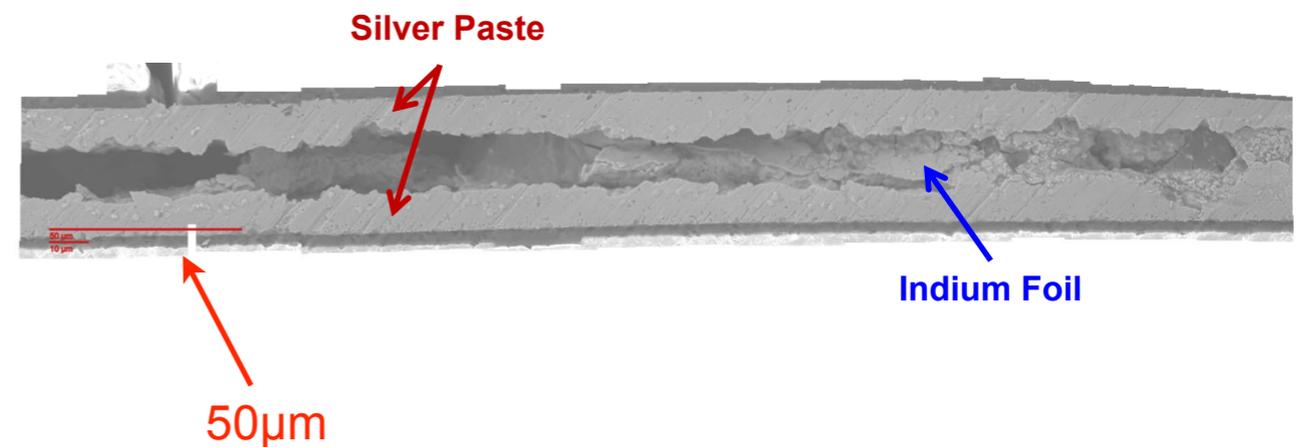


Indium Thermopressure Top Window Seal Development

- Collaborative effort with Univ. of Illinois- Chicago (Ernesto Indacochea, Alcides Raraz, Marc Kupfer)
- Bonding of top plate to sidewall must be low temperature ($\leq 150^{\circ}\text{C}$) to avoid damage to photocathode
 - Test indium cold/warm press seal to silver, chromium, or nichrome films on glass

	Temperature ($^{\circ}\text{C}$)	5 Minutes			15 minutes		
		Pressure (psi)					
		800	1000	1200	800	1000	1200
Ag coated	25				*		
	100	✓	✓	✓		*	
	125					*	
	150	✓	✓			*	
Cr coated	25						
	100		✓			*	
	125						
	150						
Cr/In coated	25						
	100						
	125		✓				
	150						

Successful Glass-Ag-In-Ag-Glass seal
 1"×1" silver ink printed glass coupons
 1000psi for 5 min., 160°C

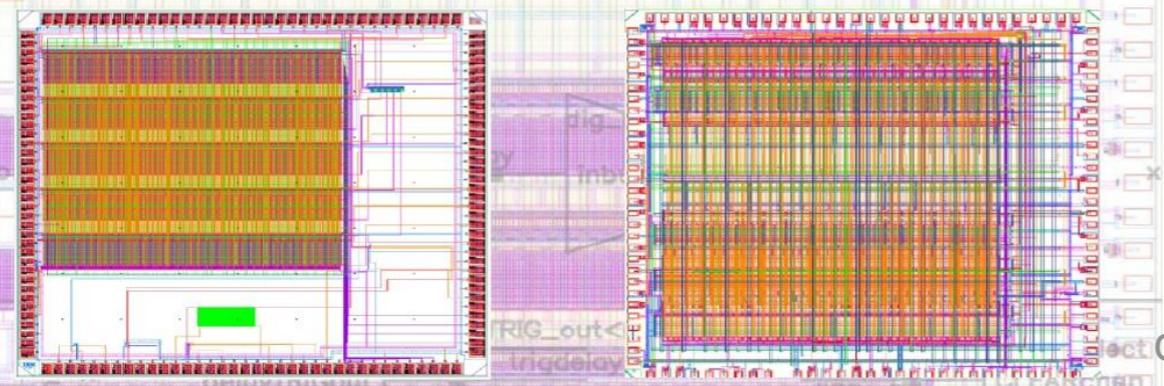




Design Status

• So far two chips have been made:

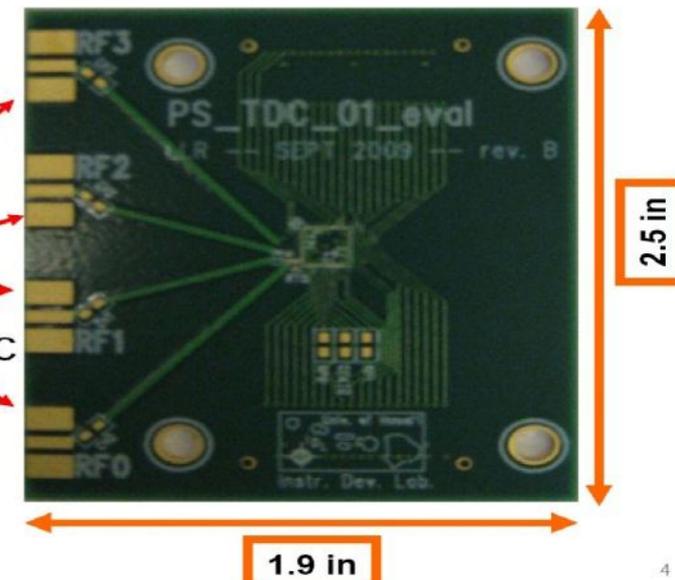
psTDC_01 psTDC_02



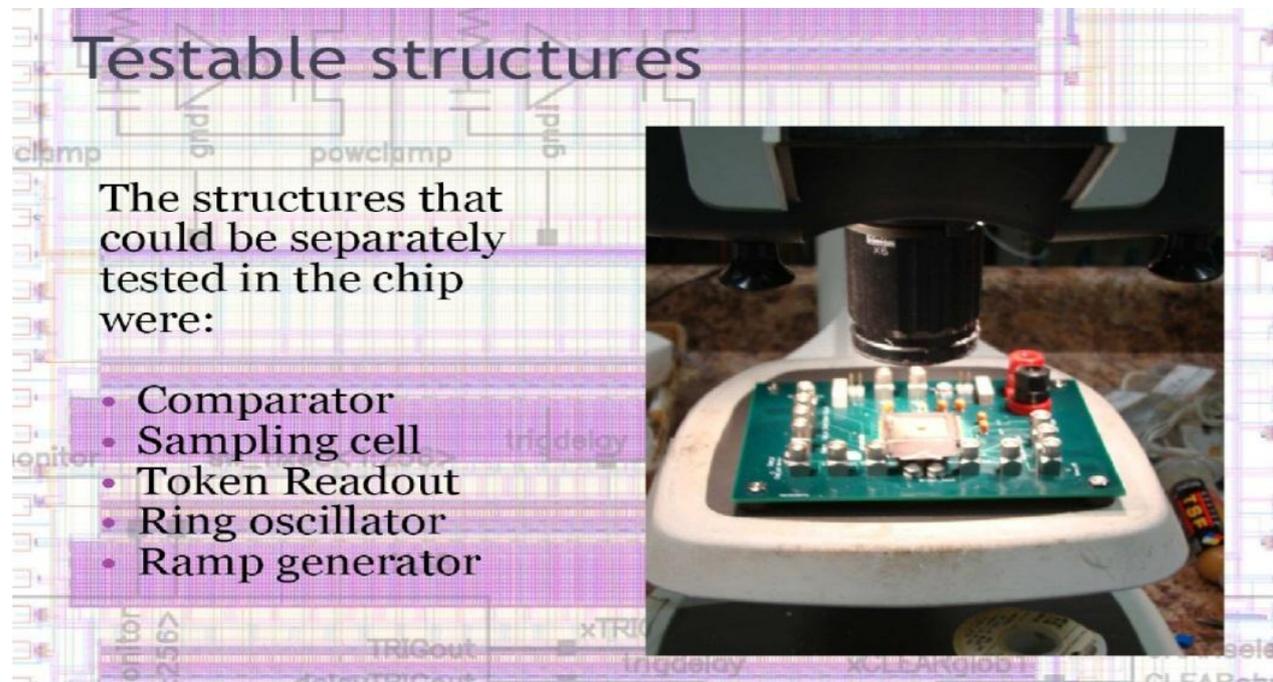
designed by students

ASIC Evaluation Card (Analog) [A.K.A. "AC card"]

- 1.9 mil (48.26 micron) trace/spacing
– laser etching
- Fairly \$\$\$ PCB fabrication
- 4x SMA input
- 2x high density Samtec connectors
- Pluggable Mezzanine card
- NP-175 dielectric



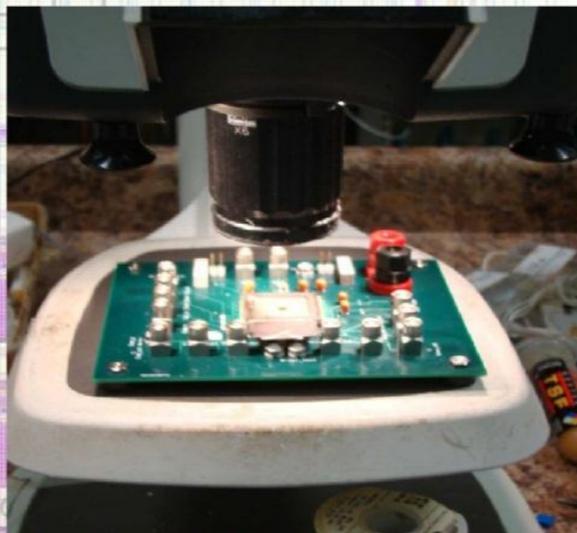
4



Testable structures

The structures that could be separately tested in the chip were:

- Comparator
- Sampling cell
- Token Readout
- Ring oscillator
- Ramp generator



designed by students

- ▶ 130nm IBM 8RF process
- ▶ 4 chs., 256 deep ring buffer
- ▶ 11 GS/s demonstrated
- ▶ ADC/ch – target 9 eff. bits
 - ADC on Psec2 non-func. due to leakage
 - Add ADC to test board
- ▶ Learning from Ritt, Breton, Delagnes, Genat*, Varner* *-> collaborators

Summary - LAPPD

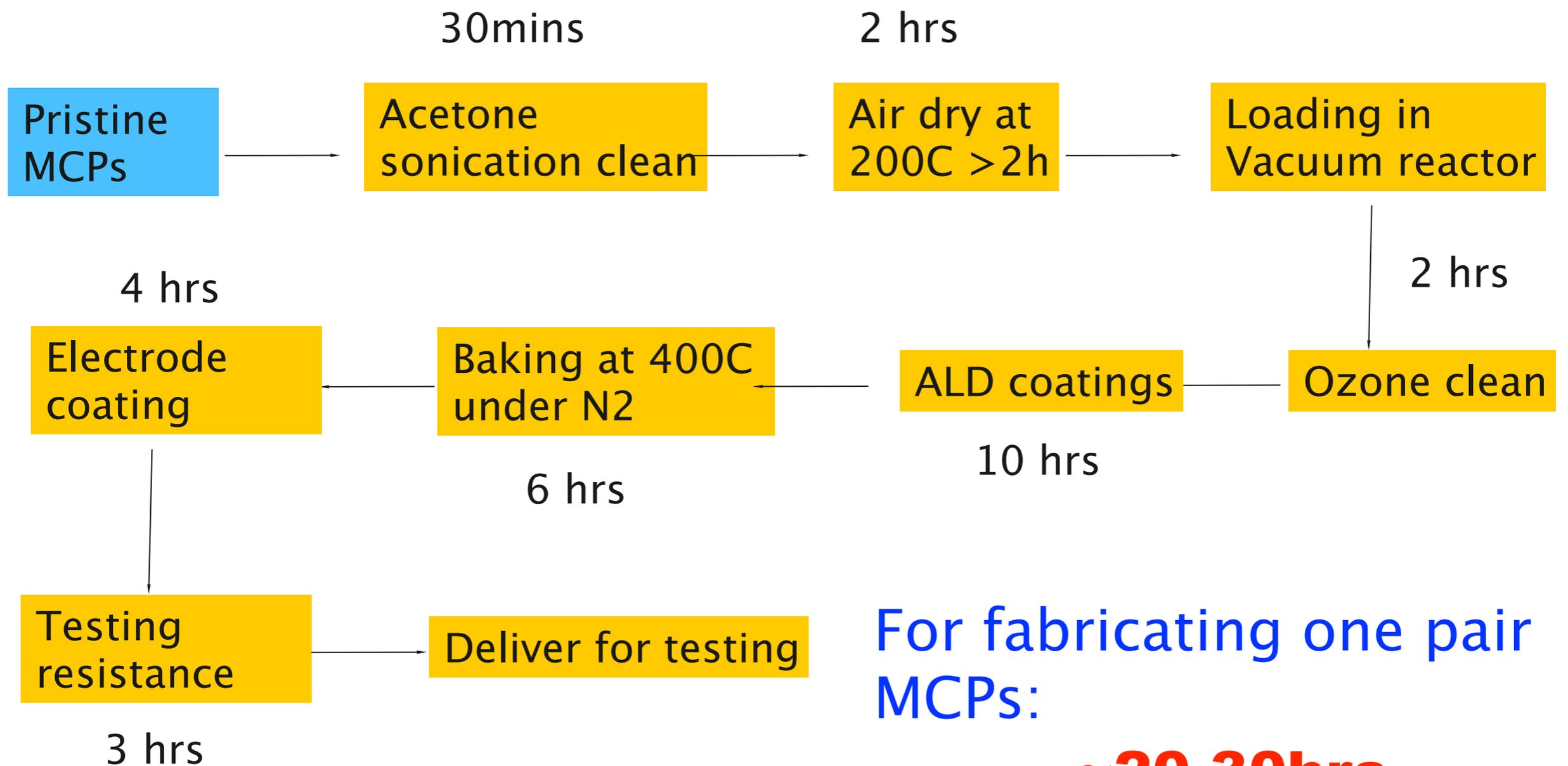
- ▶ Large Area Picosecond Photodetector Development collaboration completed 1+ year end having realized several initial goals.
- ▶ Glass capillaries look viable, working on improvements
- ▶ Atomic Layer Deposition coatings of 33mm glass capillary disks producing gain $>10^6$ for MCP pair
- ▶ Study of 3 ALD resistive + 2 ALD emissive chemistries
- ▶ Mechanical designs for hermetically sealed tube
 - Proven design in ceramic by SSL
 - Inexpensive glass design -- have demonstrated hermetic box; many other tests soon
- ▶ Developed alternative Anodic Aluminum Oxide substrate
- ▶ Design for photocathode growth and characterization facility at Argonne
- ▶ Vacuum transfer facility for 8"×8" photodetector near complete at SSL
- ▶ Photocathode fabrication and study in progress at SSL
- ▶ 8"×8" glass capillary arrays will be functionalized in next 1-2 months
- ▶ Proceeding with design & construction of tile fabrication facility at Argonne



BACKUP SLIDES



General procedures for Fabrication of MCPs



For fabricating one pair MCPs:

~20-30hrs

if everything is right

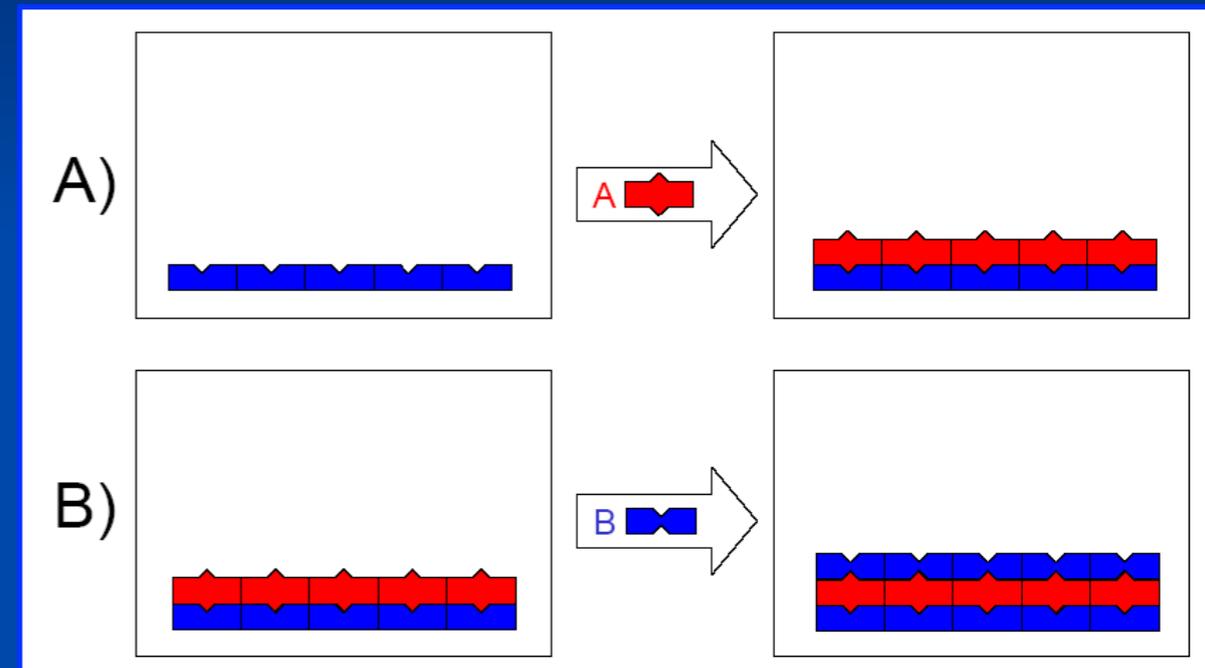
courtesy Qing Peng, Argonne ALD Group

Atomic Layer Deposition (ALD) Thin Film Coating Technology

- Lots of possible materials
=> much room for higher performance

Jeff Elam pictures

Atomic Layer Deposition (ALD) Thin Film Coating Technology

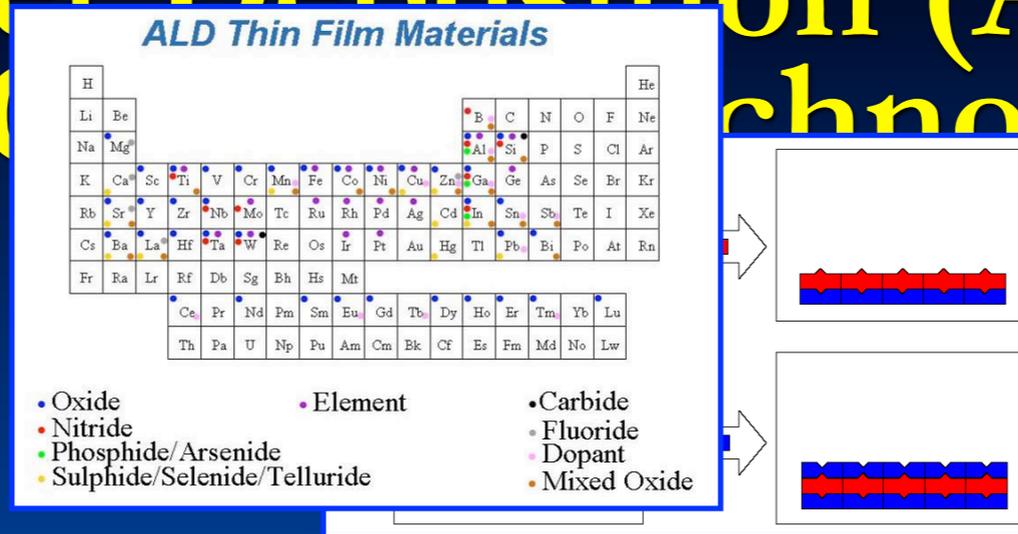


- Atomic level thickness control
- Deposit nearly any material
- Precise coatings on 3-D objects (JE)

• Lots of possible materials
=> much room for higher performance

Jeff Elam pictures

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Grid Spacer Alternative

